

EE 330

Lecture 17

MOSFET Modeling

Exam Schedule for Fall 2022

Exam 1	Friday Sept 23	
Exam 2	Friday Oct 21	
Exam 3	Friday Nov 13	
Final	Tuesday Dec 13	12:00 – 2:00 p.m.

Prelab Announcement

There will be a pre-lab posted on the class WEB site for Lab 7

Review from last lecture

Use of Piecewise Models for Nonlinear Devices when Analyzing Electronic Circuits

Single Nonlinear Device

Process:

1. Guess state of the device
2. Analyze circuit
3. Verify State
4. Repeat steps 1 to 3 if verification fails
5. Verify model (if necessary)

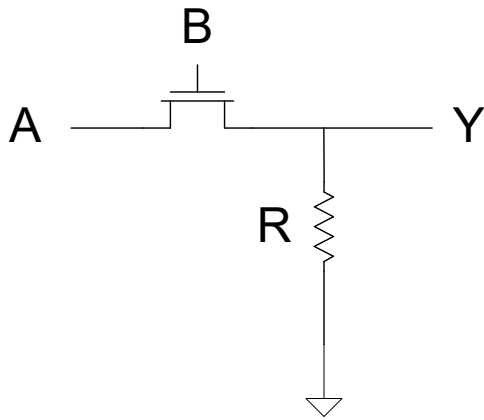
Multiple Nonlinear Devices

Process:

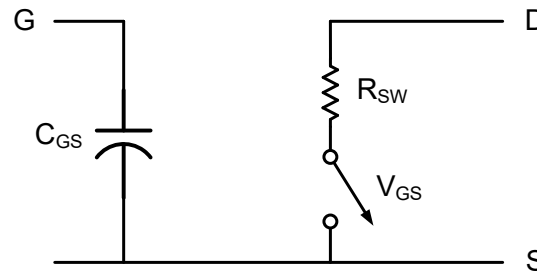
1. Guess state of each device (may be multiple combinations)
2. Analyze circuit
3. Verify State
4. Repeat steps 1 to 3 if verification fails
5. Verify models (if necessary)

Analytical solutions of circuits with multiple nonlinear devices are often impossible to obtain if detailed non-piecewise nonlinear models are used

Limitations of Existing MOSFET Models



What is Y when $A=B=V_{DD}$

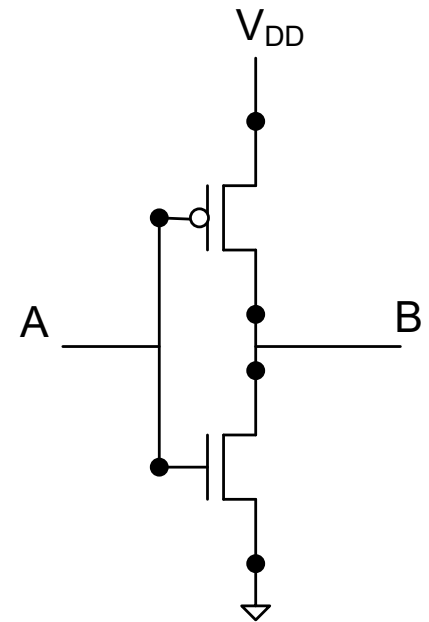


For minimum-sized devices in a 0.5u process with $V_{DD}=5V$

$$C_{GS} \cong 1.5fF$$

$$R_{sw} \cong \left. \begin{array}{l} 2K\Omega \text{ n-channel} \\ 6K\Omega \text{ p-channel} \end{array} \right\}$$

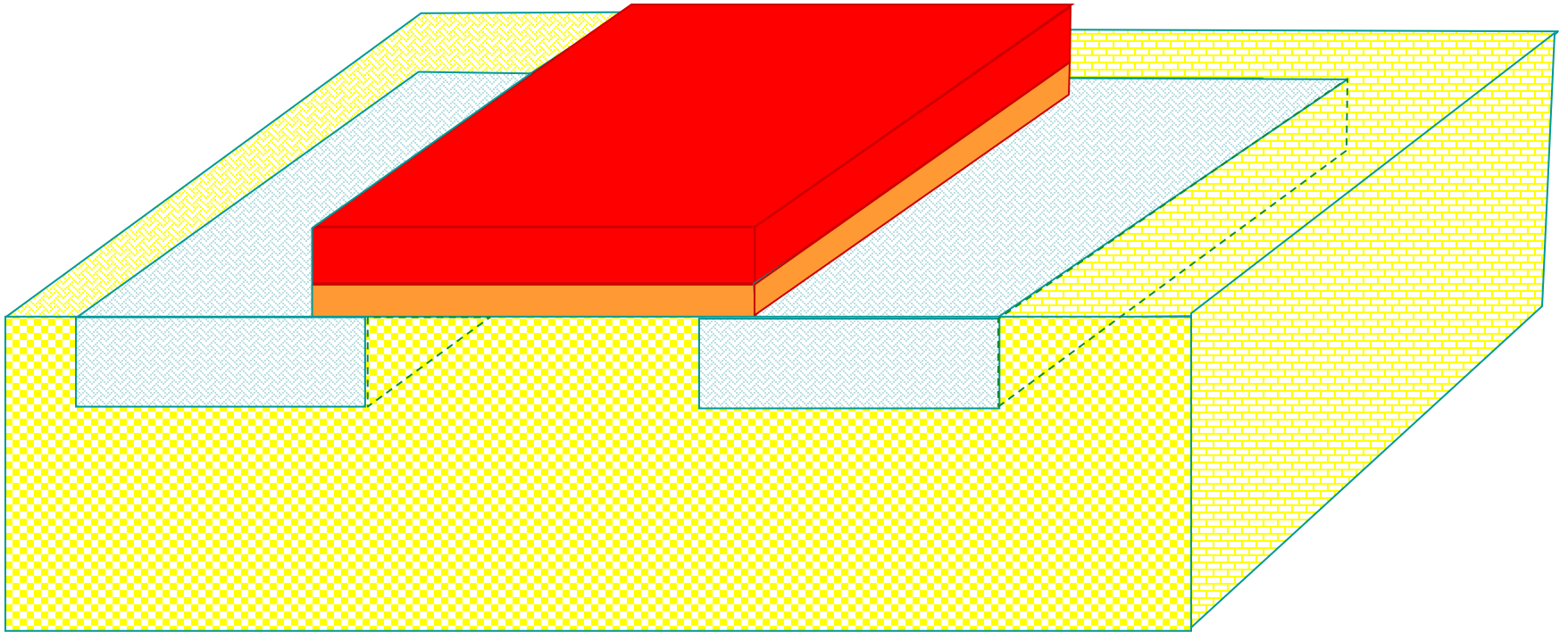
What is R_{sw} if MOSFET is not minimum sized?



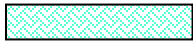



What is power dissipation if A is stuck at an intermediate voltage?

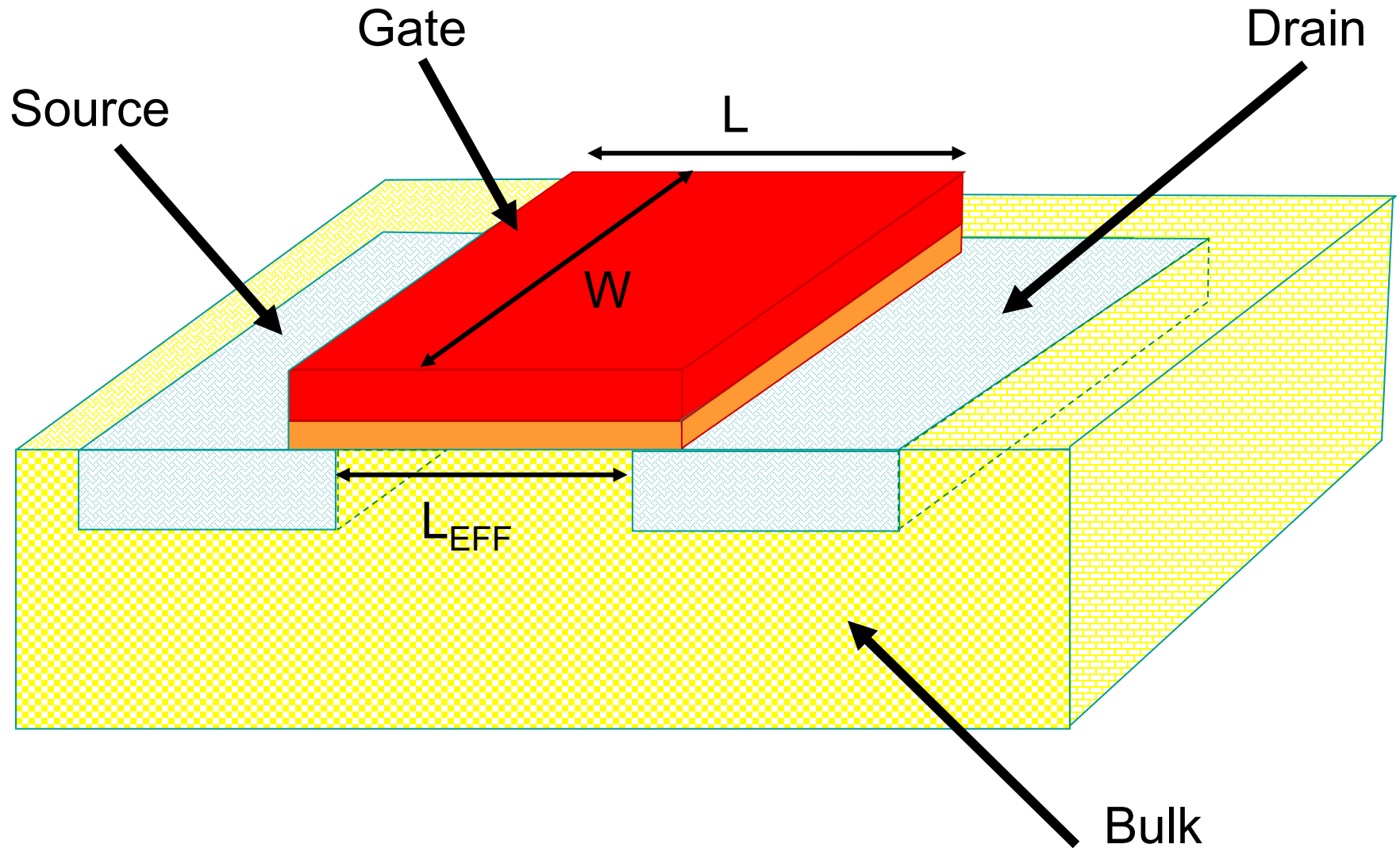
Better Model of MOSFET is Needed!

n-Channel MOSFET

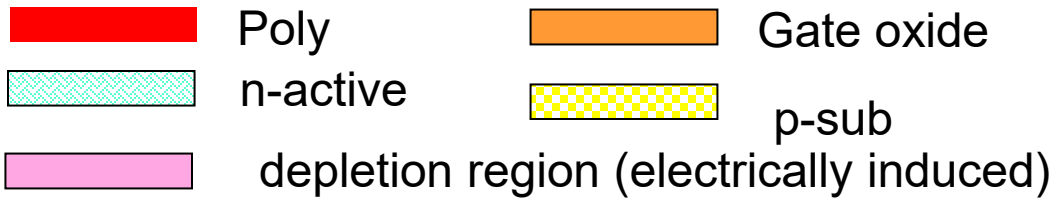
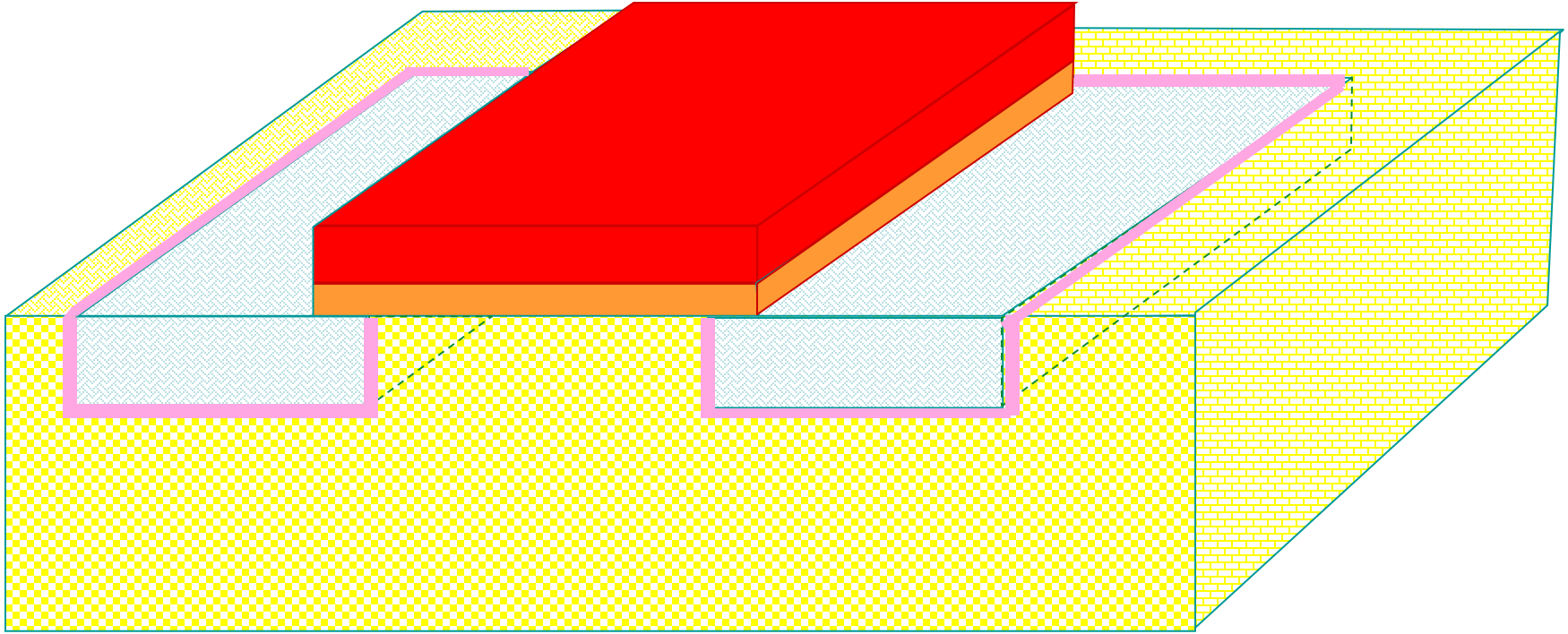


- | | | | |
|--|----------|---|------------|
|  | Poly |  | Gate oxide |
|  | n-active |  | p-sub |

n-Channel MOSFET

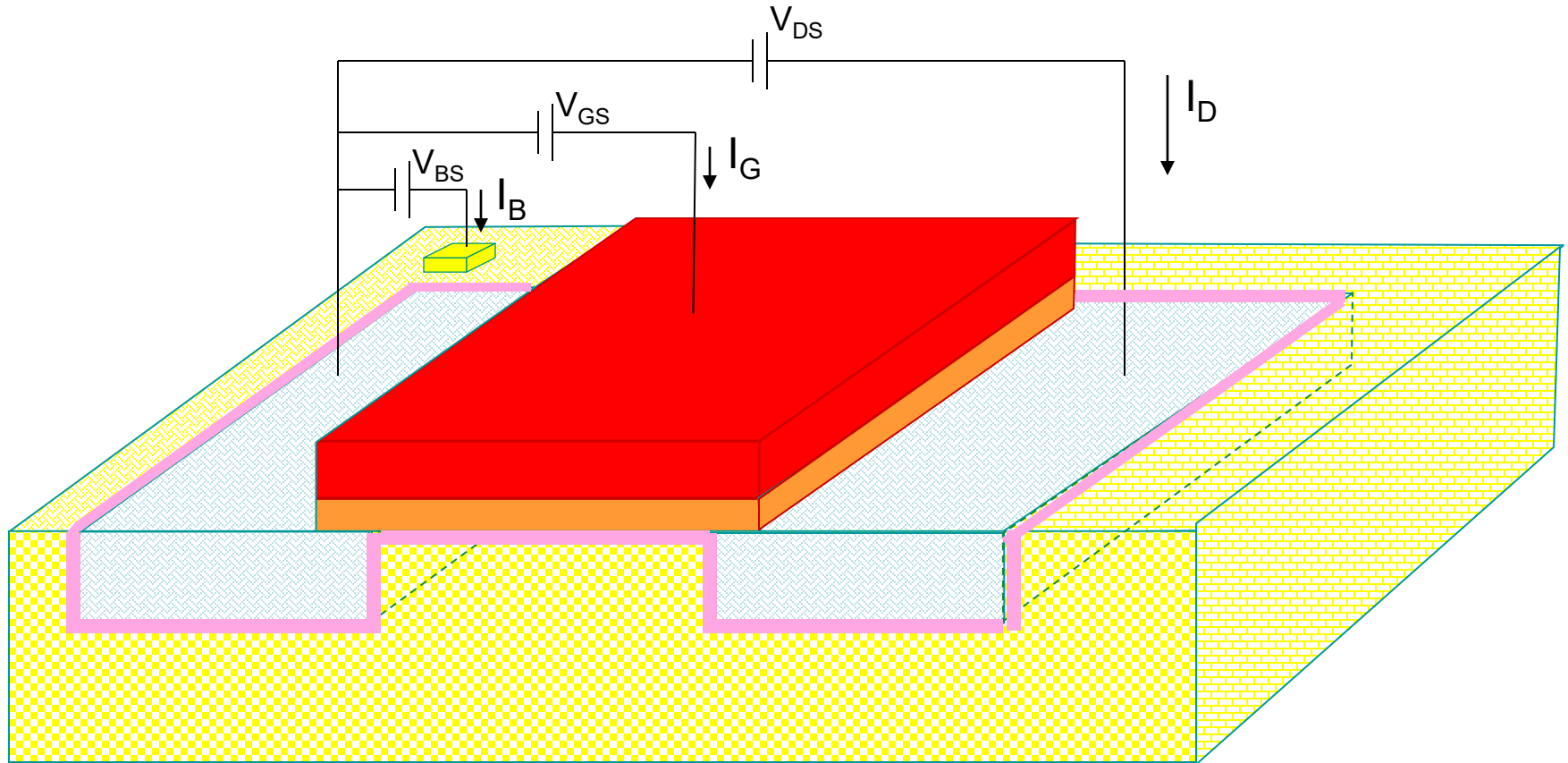


n-Channel MOSFET



- In what follows assume all pn junctions reverse biased (almost always used this way)
- Extremely small reverse bias pn junction current can be neglected in most applications

n-Channel MOSFET Operation and Model



Apply small V_{GS}

(V_{DS} and V_{BS} assumed to be small)

Depletion region electrically induced in channel

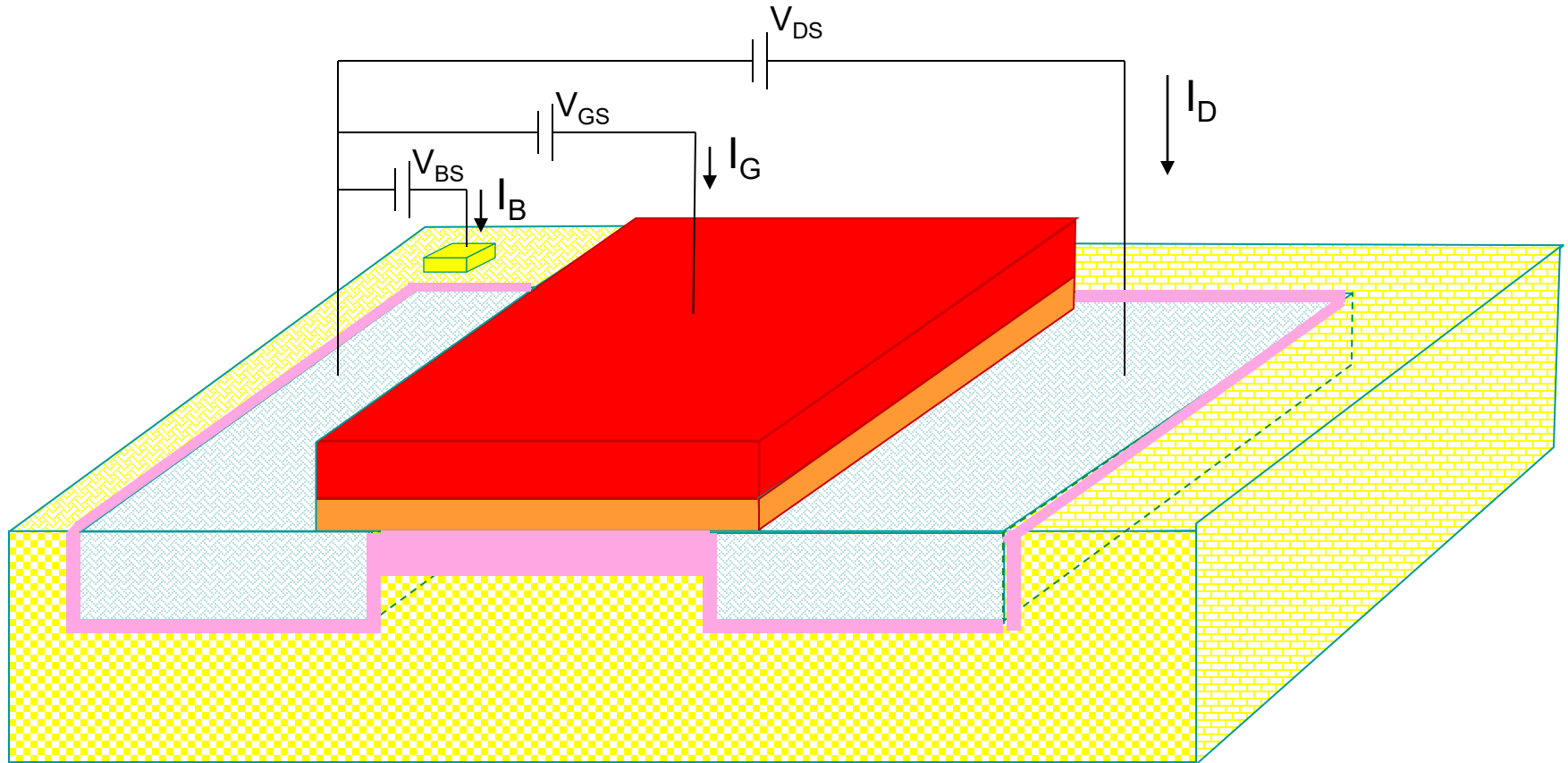
Termed “cutoff” region of operation

$$I_D = 0$$

$$I_G = 0$$

$$I_B = 0$$

n-Channel MOSFET Operation and Model

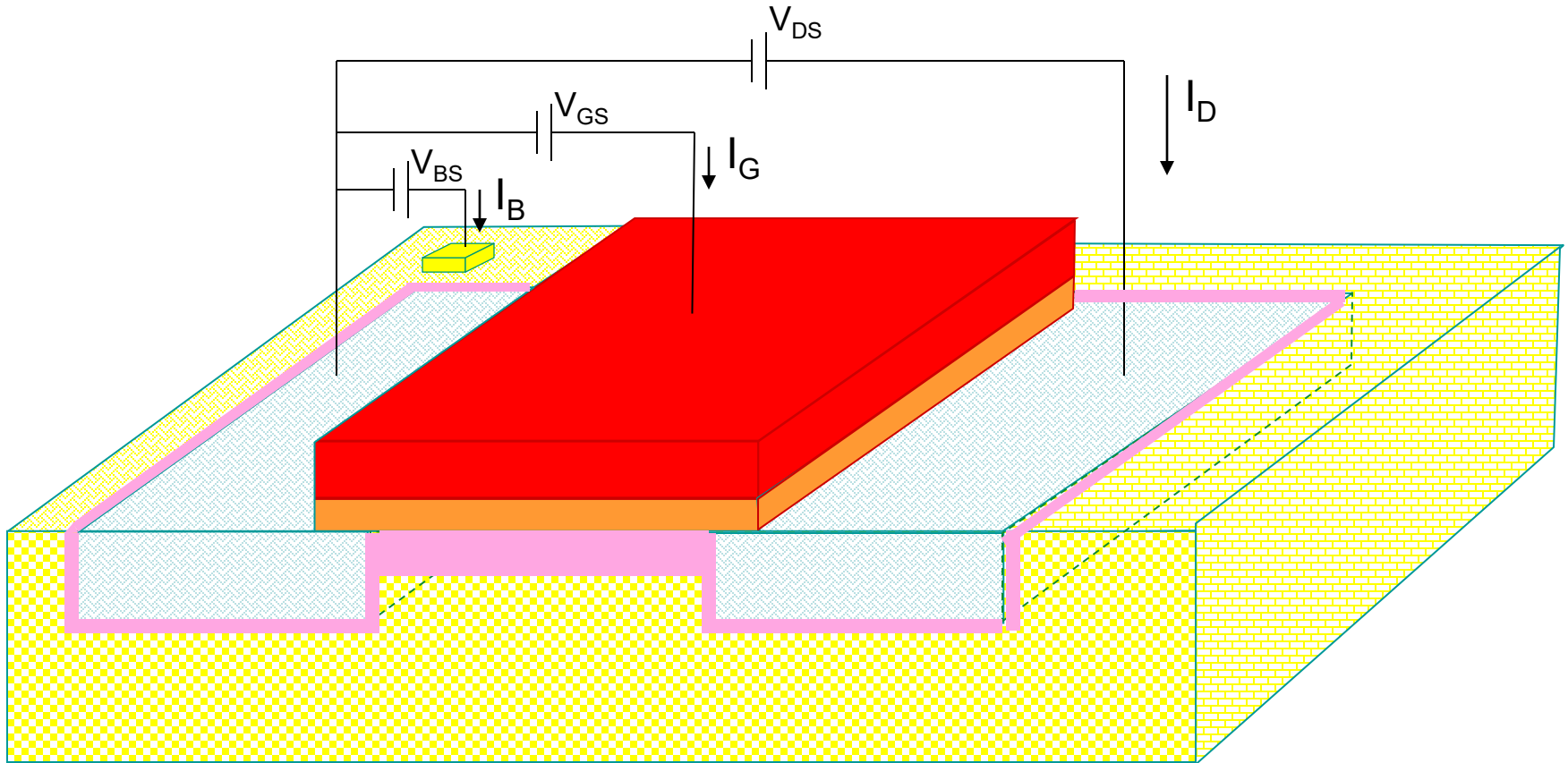


Increase V_{GS}
(V_{DS} and V_{BS} assumed to be small)

Depletion region in channel becomes larger

$$\begin{aligned} I_D &= 0 \\ I_G &= 0 \\ I_B &= 0 \end{aligned}$$

n-Channel MOSFET Operation and Model



$$I_D = 0$$

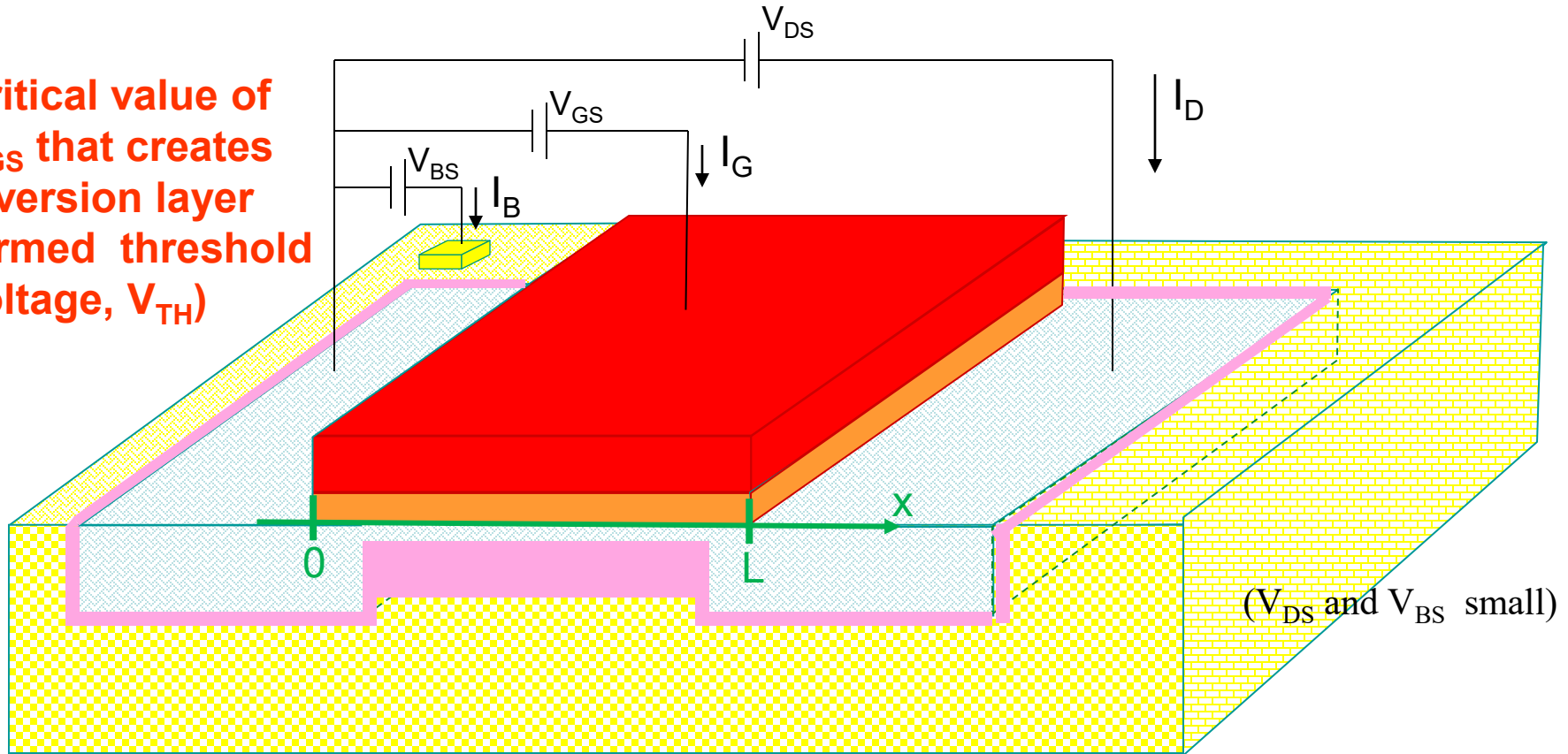
$$I_G = 0$$

$$I_B = 0$$

Model in Cutoff Region

n-Channel MOSFET Operation and Model

Critical value of V_{GS} that creates inversion layer termed threshold voltage, V_{TH})



Increase V_{GS} more

Inversion layer forms in channel

Inversion layer will support current flow from D to S

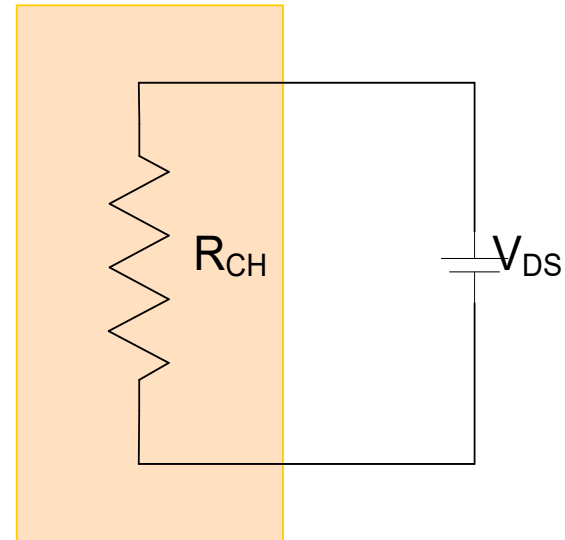
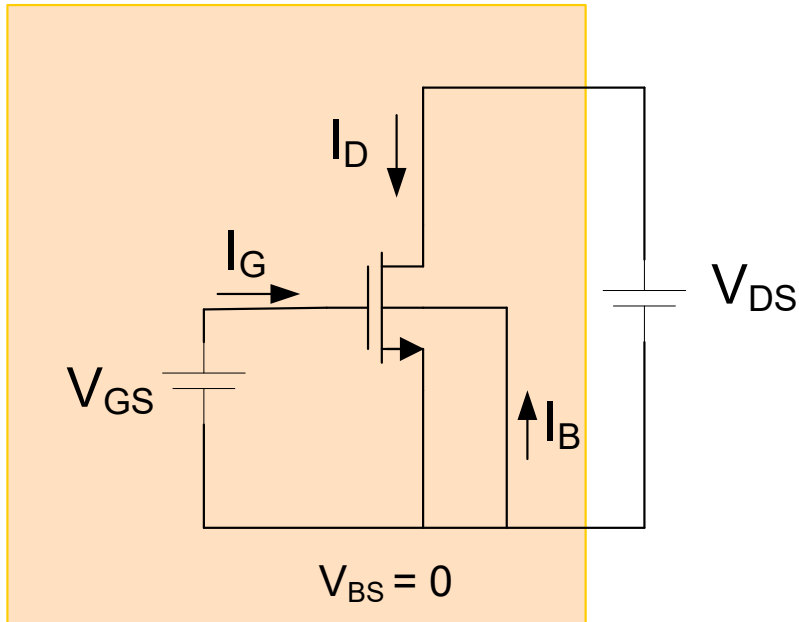
Channel behaves as thin-film resistor

$$I_D R_{CH} = V_{DS}$$

$$I_G = 0$$

$$I_B = 0$$

Triode Region of Operation



For V_{DS} small and $V_{GS} > V_{TH}$

$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{OX}}$$

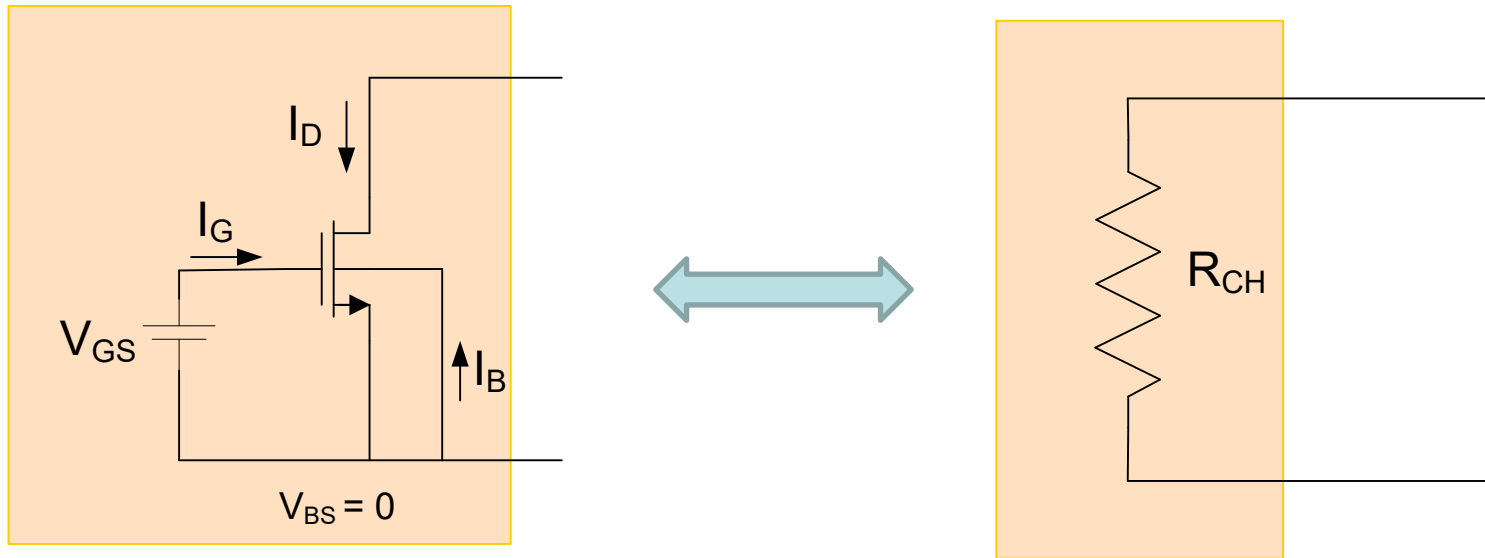
Behaves as a resistor between drain and source

$$I_D = \mu C_{OX} \frac{W}{L} (V_{GS} - V_{TH}) V_{DS}$$

$$I_G = I_B = 0$$

Model in Deep Triode Region

Triode Region of Operation

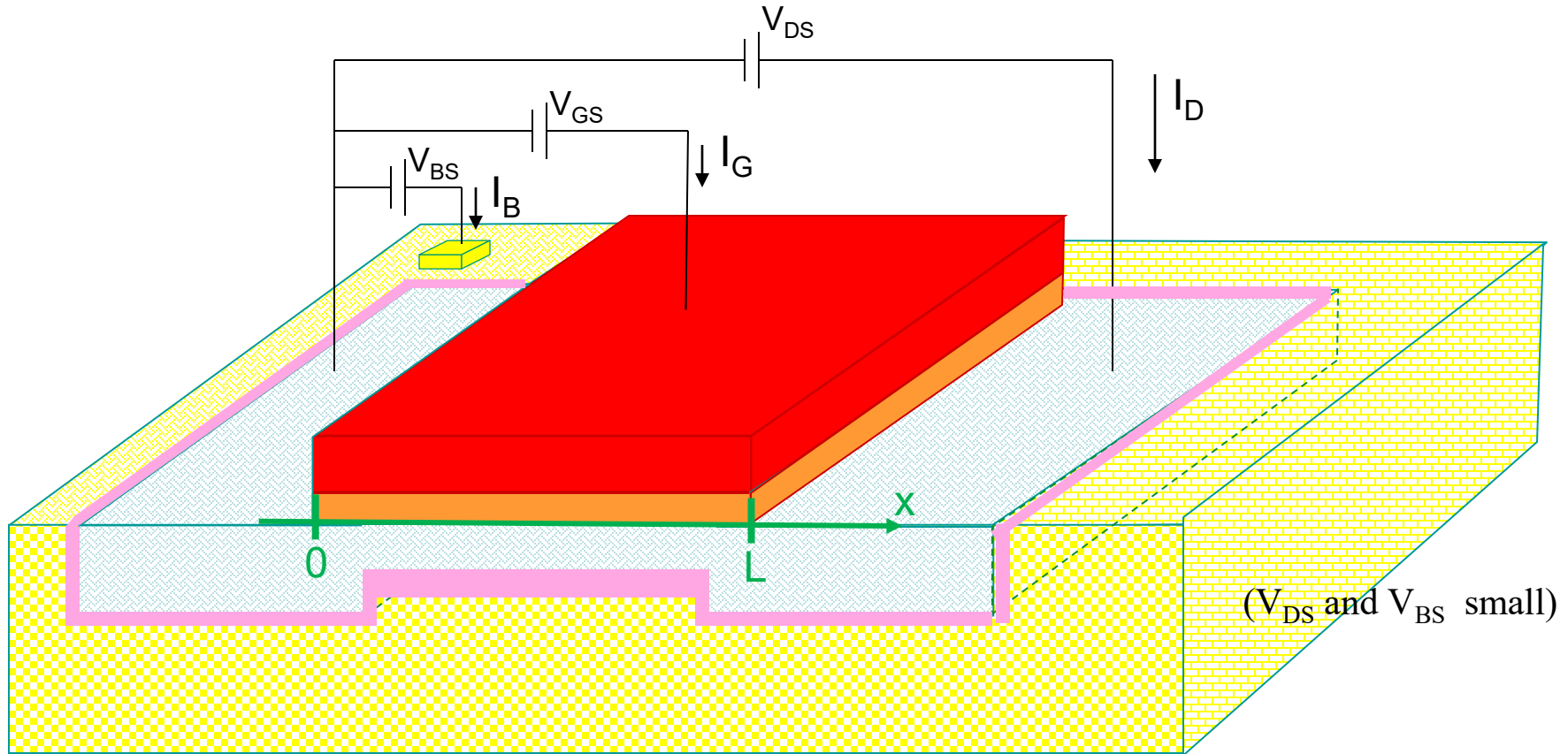


For V_{DS} small and $V_{GS} > V_{TH}$

$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{OX}}$$

Resistor is controlled by the voltage V_{GS}
Termed a “Voltage Controlled Resistor” (VCR)

n-Channel MOSFET Operation and Model



Increase V_{GS} more with $V_{GS} > V_{TH}$ $V_{GC}(x)$ approx. constant for small V_{DS}

Inversion layer in channel thickens

R_{CH} will decrease

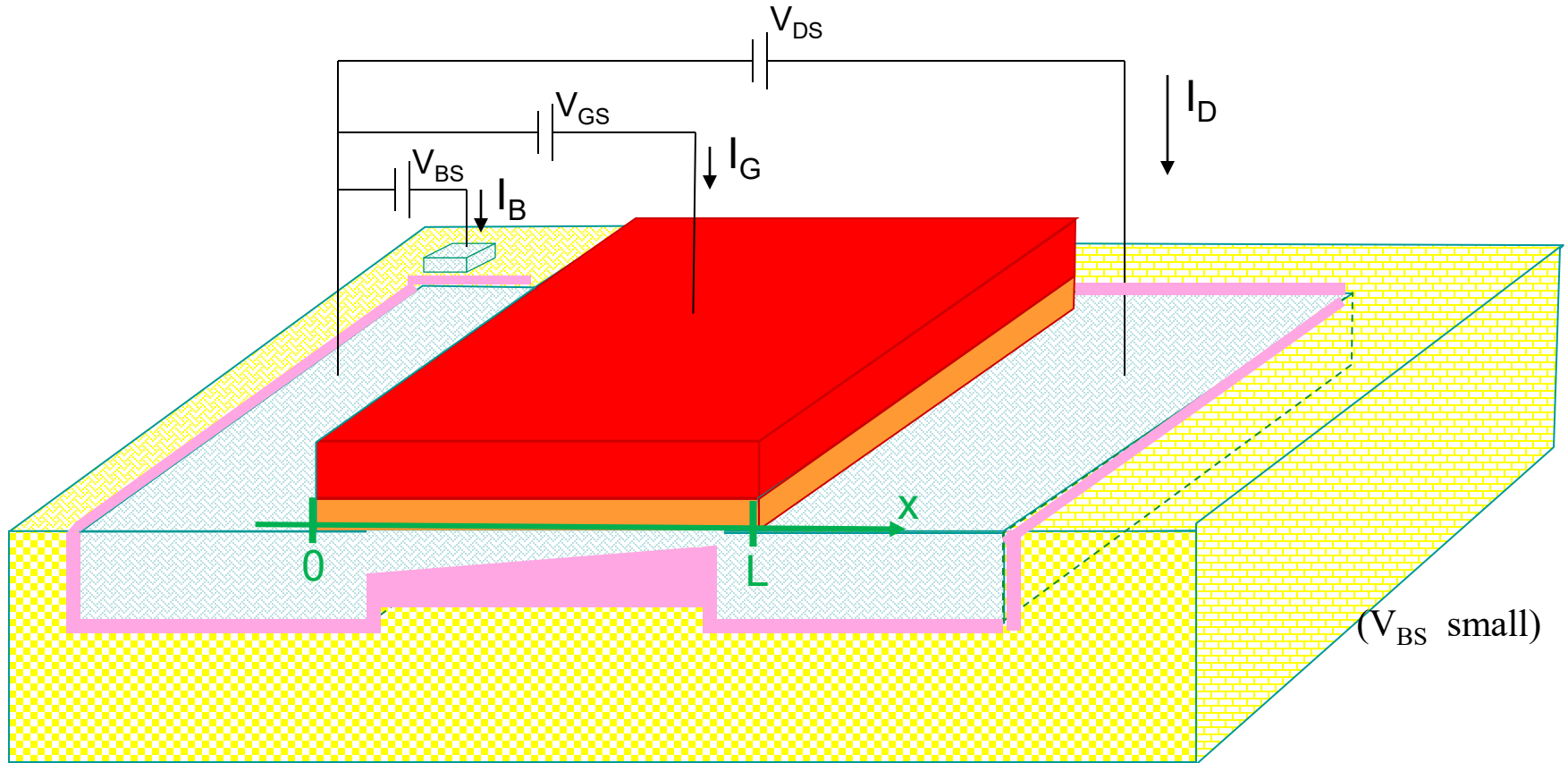
Termed "ohmic" or "triode" region of operation

$$I_D R_{CH} = V_{DS}$$

$$I_G = 0$$

$$I_B = 0$$

n-Channel MOSFET Operation and Model



Increase V_{DS} and $V_{GS} > V_{TH}$

$V_{GC}(x)$ changes with x for larger V_{DS}

Inversion layer thins near drain

I_D no longer linearly dependent upon V_{DS}

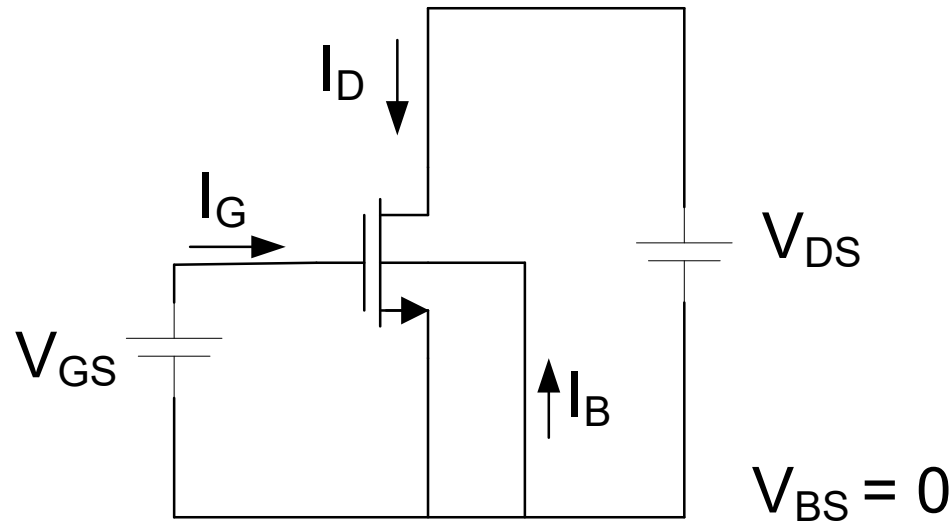
Still termed “ohmic” or “triode” region of operation

$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

Triode Region of Operation



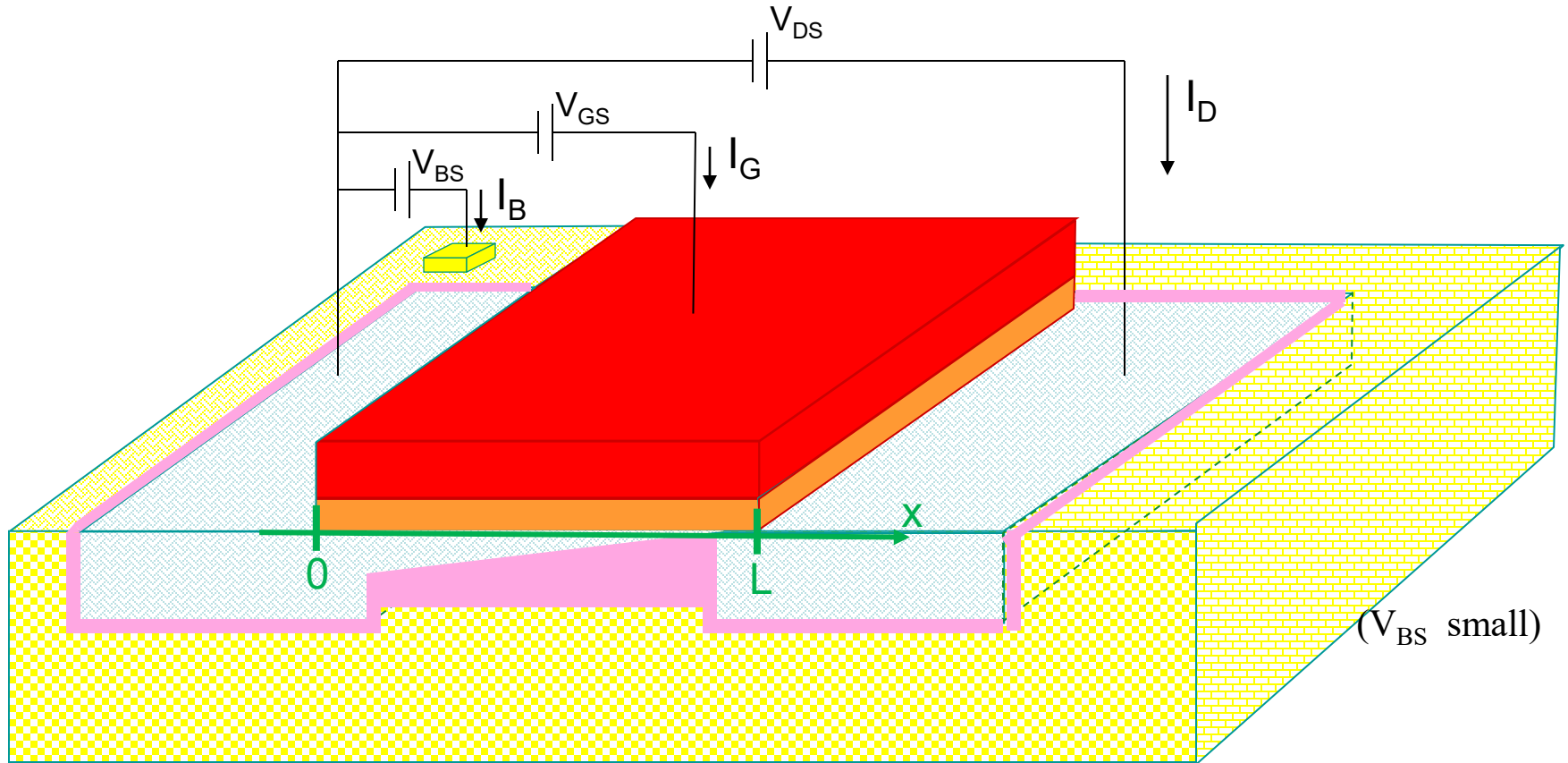
For V_{DS} larger and $V_{GS} > V_{TH}$

~~$$R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_{TH}) \mu C_{OX}}$$~~

$$I_D = \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$
$$I_G = I_B = 0$$

Model in Triode Region

n-Channel MOSFET Operation and Model



Increase V_{DS} even more

$V_{GC}(L) = V_{TH}$ when channel saturates

Inversion layer disappears near drain

Termed "saturation" region of operation

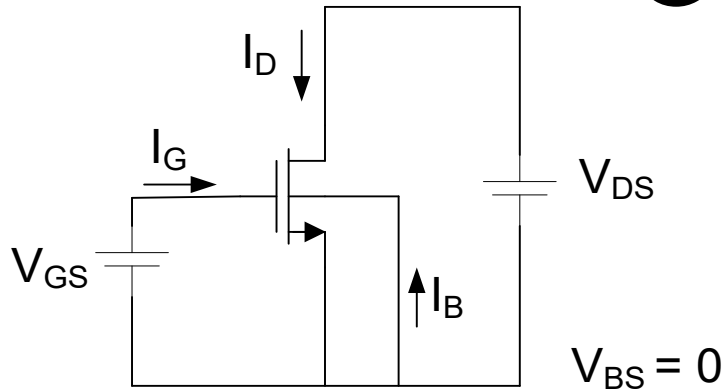
Saturation first occurs when $V_{DS} = V_{GS} - V_{TH}$

$$I_D = ?$$

$$I_G = 0$$

$$I_B = 0$$

Saturation Region of Operation



$$I_D = \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_{TH} - \frac{V_{DS}}{2} \right) V_{DS}$$

or equivalently

$$I_D = \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_{TH} - \frac{V_{GS} - V_{TH}}{2} \right) (V_{GS} - V_{TH})$$

or equivalently

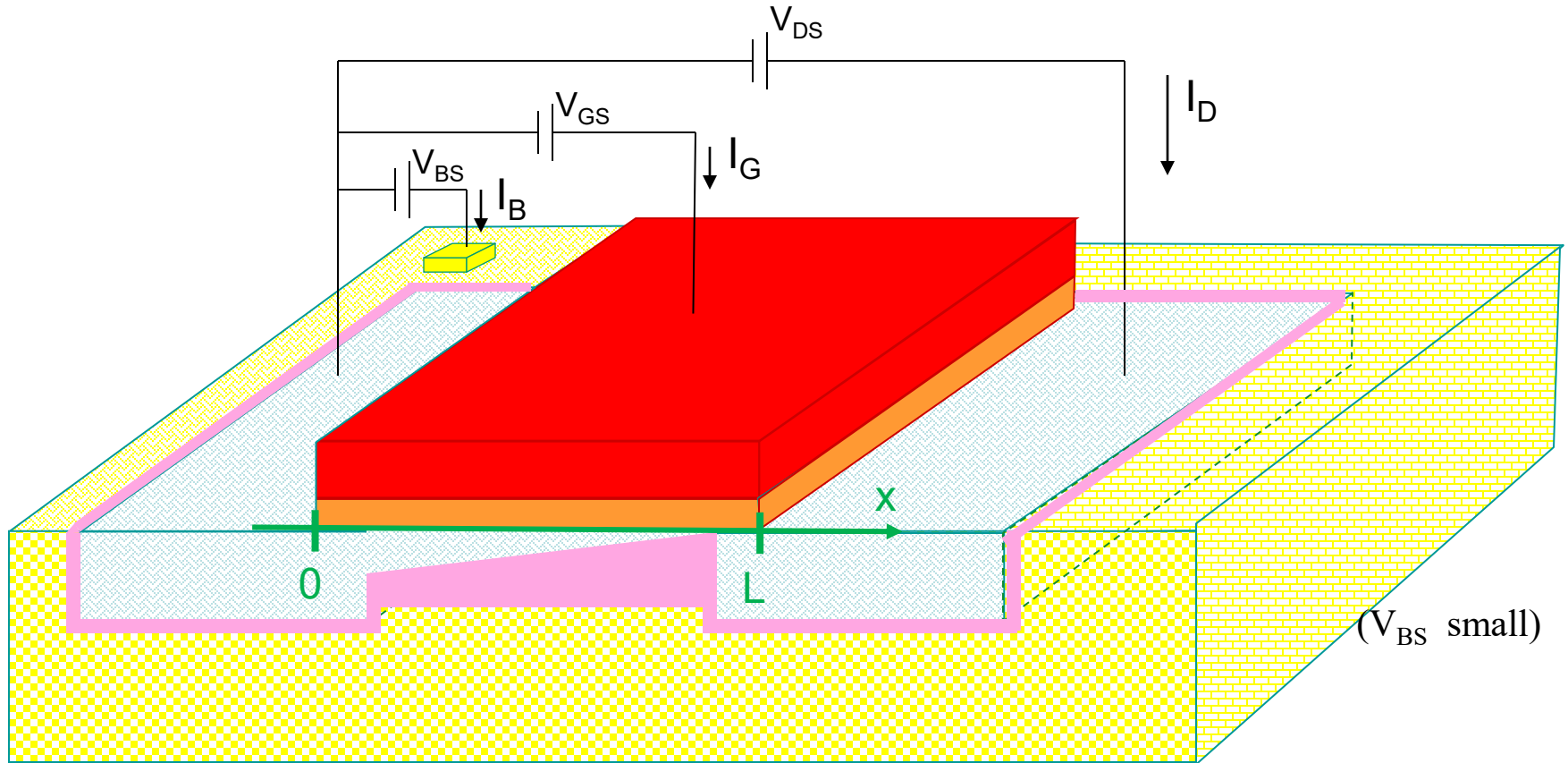
$$I_D = \frac{\mu C_{OX} W}{2L} (V_{GS} - V_{TH})^2$$

$$I_G = I_B = 0$$

For V_{DS} at onset of saturation

$$V_{DS} = V_{GS} - V_{TH}$$

n-Channel MOSFET Operation and Model



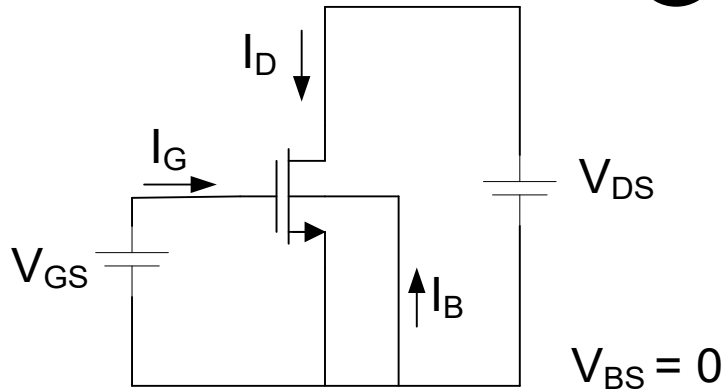
Increase V_{DS} even more (beyond $V_{GS} - V_{TH}$)

Nothing much changes !!

Termed "saturation" region of operation

$$\begin{aligned} I_D &=? \\ I_G &=0 \\ I_B &=0 \end{aligned}$$

Saturation Region of Operation



For V_{DS} in Saturation

$$I_D = \frac{\mu C_{OX} W}{2L} (V_{GS} - V_{TH})^2$$

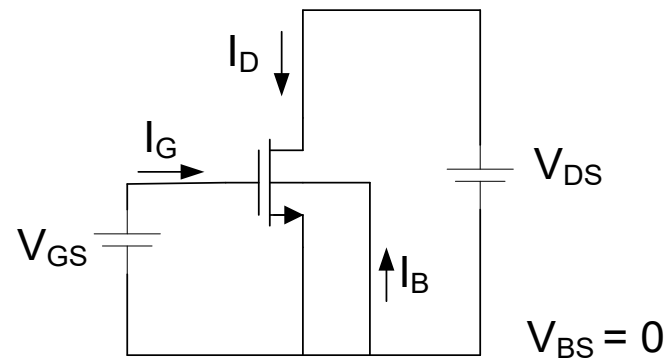
$$I_G = I_B = 0$$

Model in Saturation Region

Model Summary

n-channel MOSFET

Notation change: $V_T = V_{TH}$, don't confuse V_T with $V_t = kT/q$



$$I_D = \begin{cases} 0 & V_{GS} \leq V_T & \text{Cutoff} \\ \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T & \text{Triode} \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T & \text{Saturation} \end{cases}$$

$$I_G = I_B = 0$$

Model Parameters: $\{\mu, V_T, C_{OX}\}$ Design Parameters : $\{W, L\}$

This is a piecewise model (not piecewise linear though)

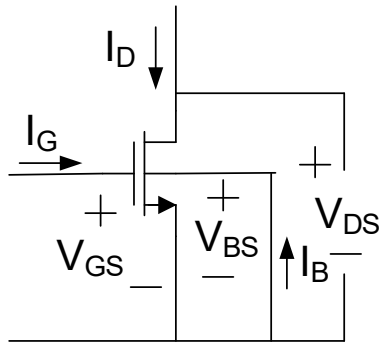
Piecewise model is continuous at transition between regions

(Deep triode special case of triode where V_{DS} is small $R_{CH} = \frac{L}{W} \frac{1}{(V_{GS} - V_T) \mu C_{OX}}$)

Note: This is the third model we have introduced for the MOSFET

Model Summary

n-channel MOSFET



$V_{BS} = 0$

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$I_G = I_B = 0$$

Observations about this model (developed for $V_{BS}=0$):

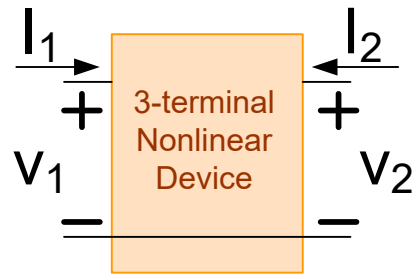
$$I_D = f_1(V_{GS}, V_{DS})$$

$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

This is a nonlinear piecewise model characterized by the functions f_1 , f_2 , and f_3 where we have assumed that the port voltages V_{GS} and V_{DS} are the independent variables and the drain currents are the dependent variables

General Nonlinear Models

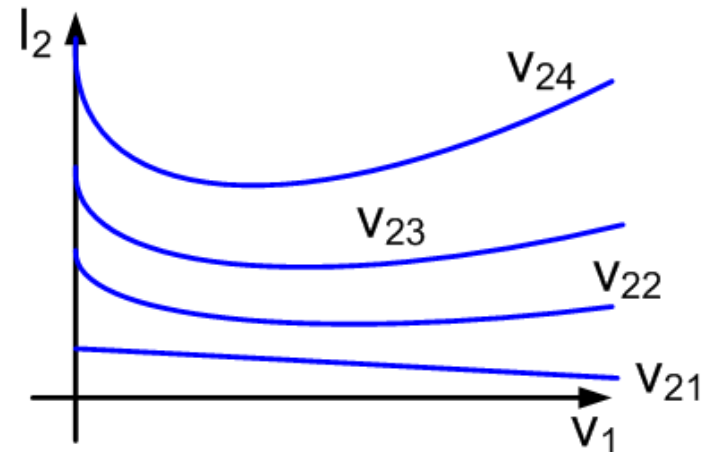
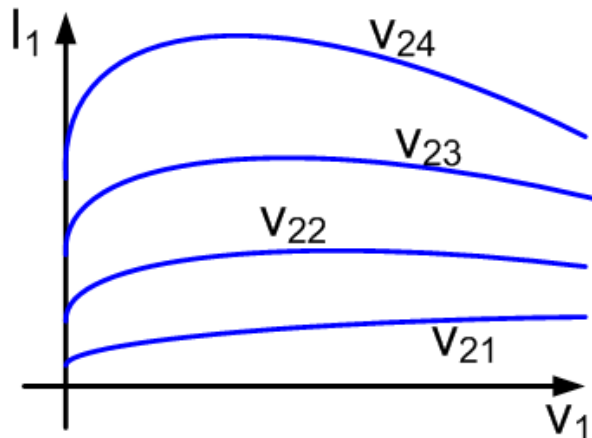


$$I_1 = f_1(V_1, V_2)$$

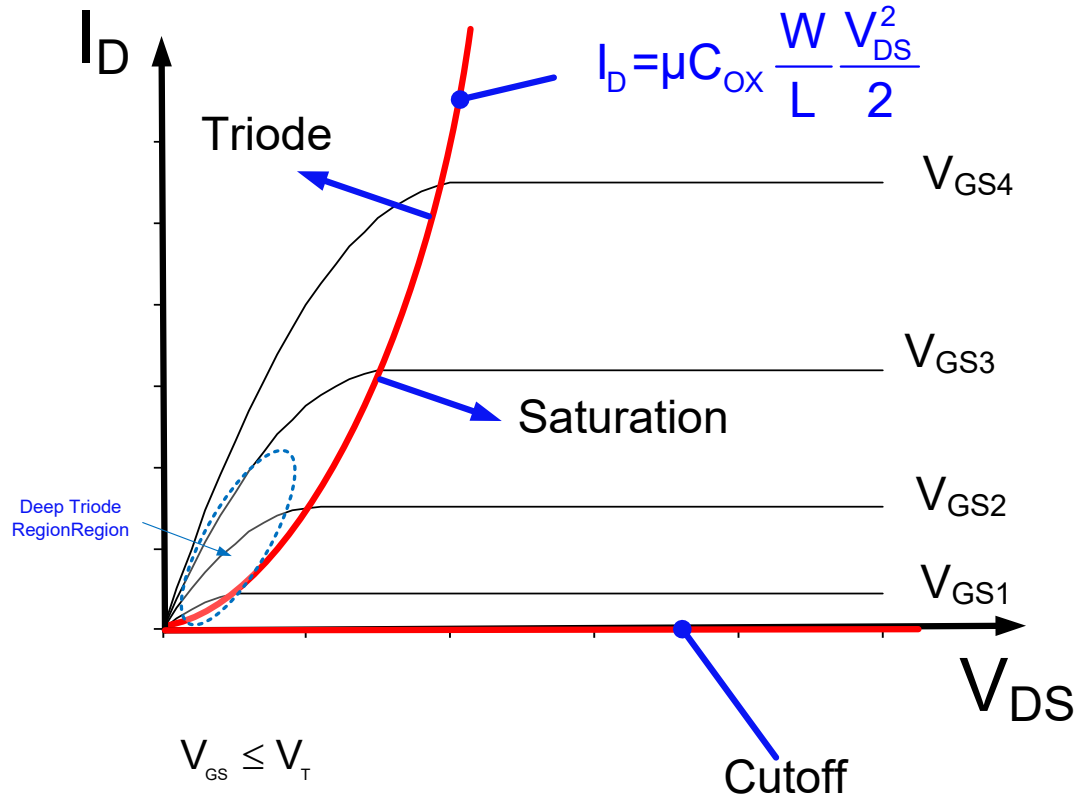
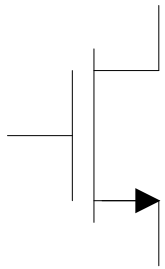
$$I_2 = f_2(V_1, V_2)$$

I_1 and I_2 are 3-dimensional relationships which are often difficult to visualize

Two-dimensional representation of 3-dimensional relationships



Graphical Representation of MOS Model

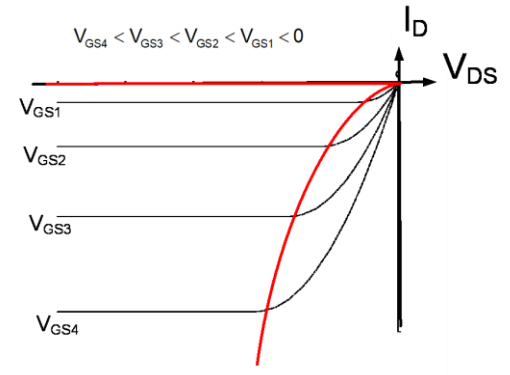
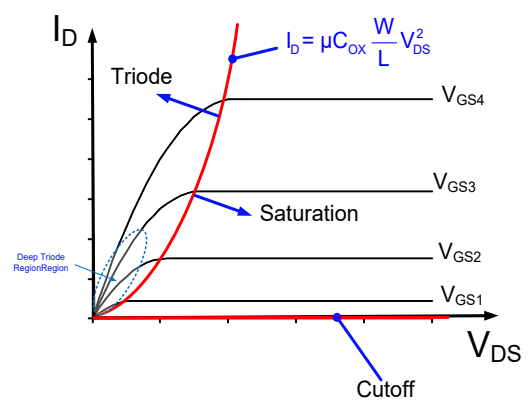
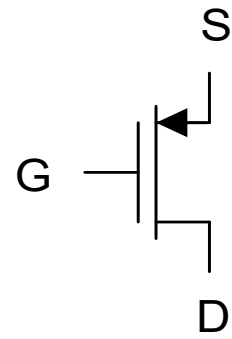
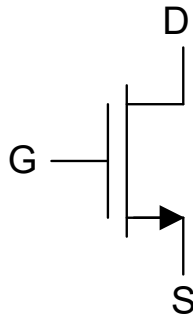


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T, V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T, V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$I_G = I_B = 0$$

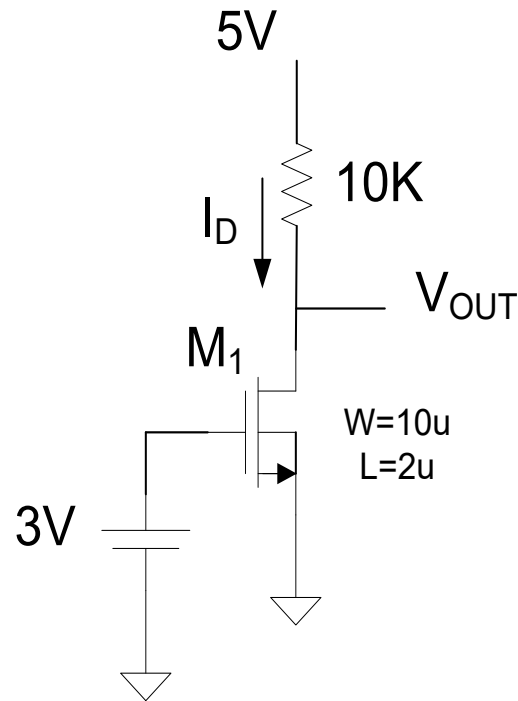
Parabola separated triode and saturation regions and corresponds to $V_{DS} = V_{GS} - V_T$

PMOS and NMOS Models



- Functional form identical, sign changes and parameter values different
- Will give details about p-channel model later

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu AV^{-2}$

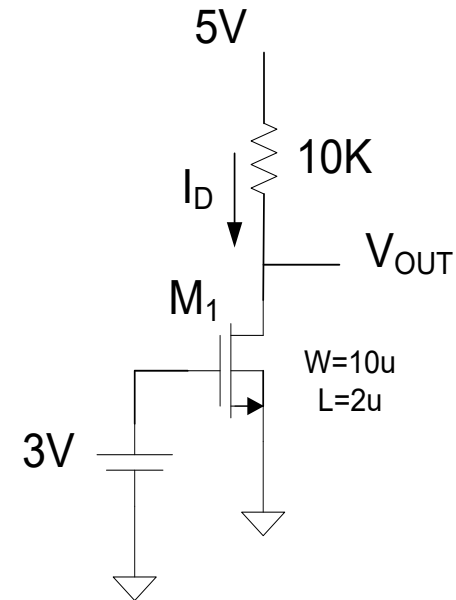


Solution:

Since $V_{GS} > V_T$, M_1 is operating in either saturation or triode region

Strategy will be to guess region of operation, solve, and then verify region

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu AV^{-2}$



Solution:

Guess M_1 in saturation

$$5V = I_D 10K + V_{OUT}$$

$$I_D = \frac{\mu C_{OX} W}{2L} (3 - V_T)^2$$

Required verification: $V_{DS} > V_{GS} - V_T$

Can eliminate I_D between these 2 equations to obtain V_{OUT}

Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu AV^{-2}$

Guess M_1 in saturation

Required verification: $V_{DS} > V_{GS} - V_T$

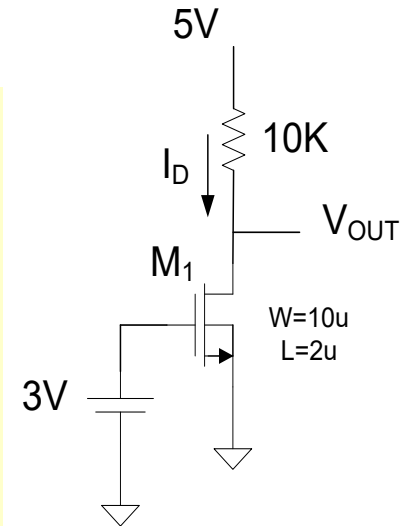
$$\left. \begin{aligned} 5V &= I_D 10K + V_{OUT} \\ I_D &= \frac{\mu C_{OX} W}{2L} (3 - V_T)^2 \end{aligned} \right\}$$

$$V_{OUT} = 5V - 10K \left[\frac{100\mu AV^{-2} 10\mu}{2 \cdot 2\mu} (2V)^2 \right]$$

$$V_{OUT} = -5V$$

Verification: $V_{DS} = V_{OUT}$

$-5 >? 2V - 0$ No! So verification fails and Guess of region is invalid



Example: Determine the output voltage for the following circuit using the square-law model of the MOSFET. Assume $V_T=1V$ and $\mu C_{OX}=100\mu AV^{-2}$

Guess M_1 in triode

Required verification: $V_{DS} < V_{GS} - V_T$

$$5V = I_D 10K + V_{OUT}$$

$$I_D = \frac{\mu C_{OX} W}{L} \left(3 - V_T - \frac{V_{DS}}{2} \right) V_{DS}$$

$$V_{OUT} = 5V - 10K \left[\frac{100\mu AV^{-2} 10\mu}{2\mu} \left(2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

$$V_{OUT} = 5V - \left[5 \left(2V - \frac{V_{OUT}}{2} \right) V_{OUT} \right]$$

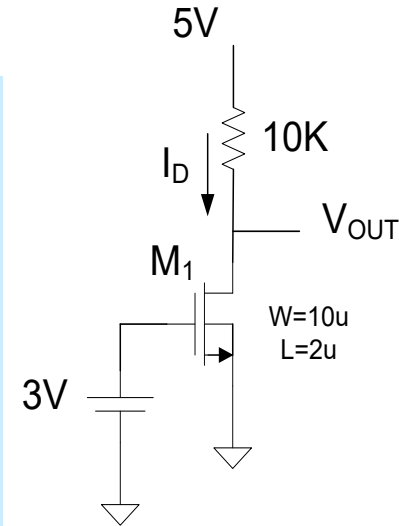
Solving for V_{OUT} , obtain

$$V_{OUT} = 0.515V$$

Verification: $V_{DS} = V_{OUT}$

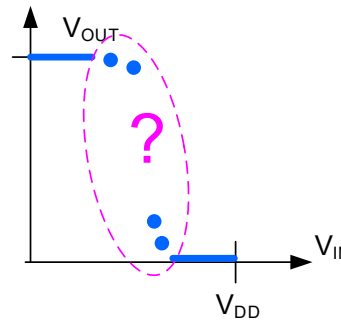
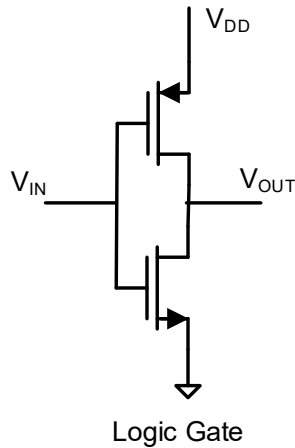
$0.515 <? 2V$ Yes!

So verification succeeds and triode region is valid

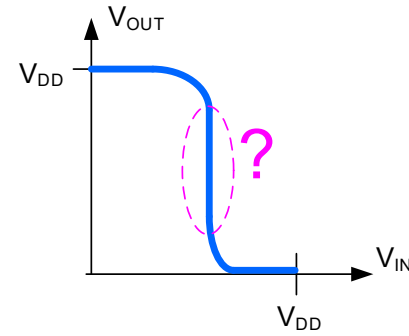


$$V_{OUT} = 0.515V$$

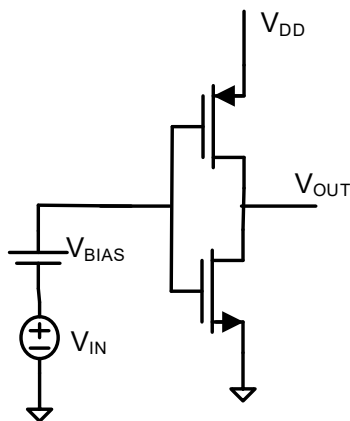
Limitations of Existing Models



Switch-Level Models



Simple square-law Model



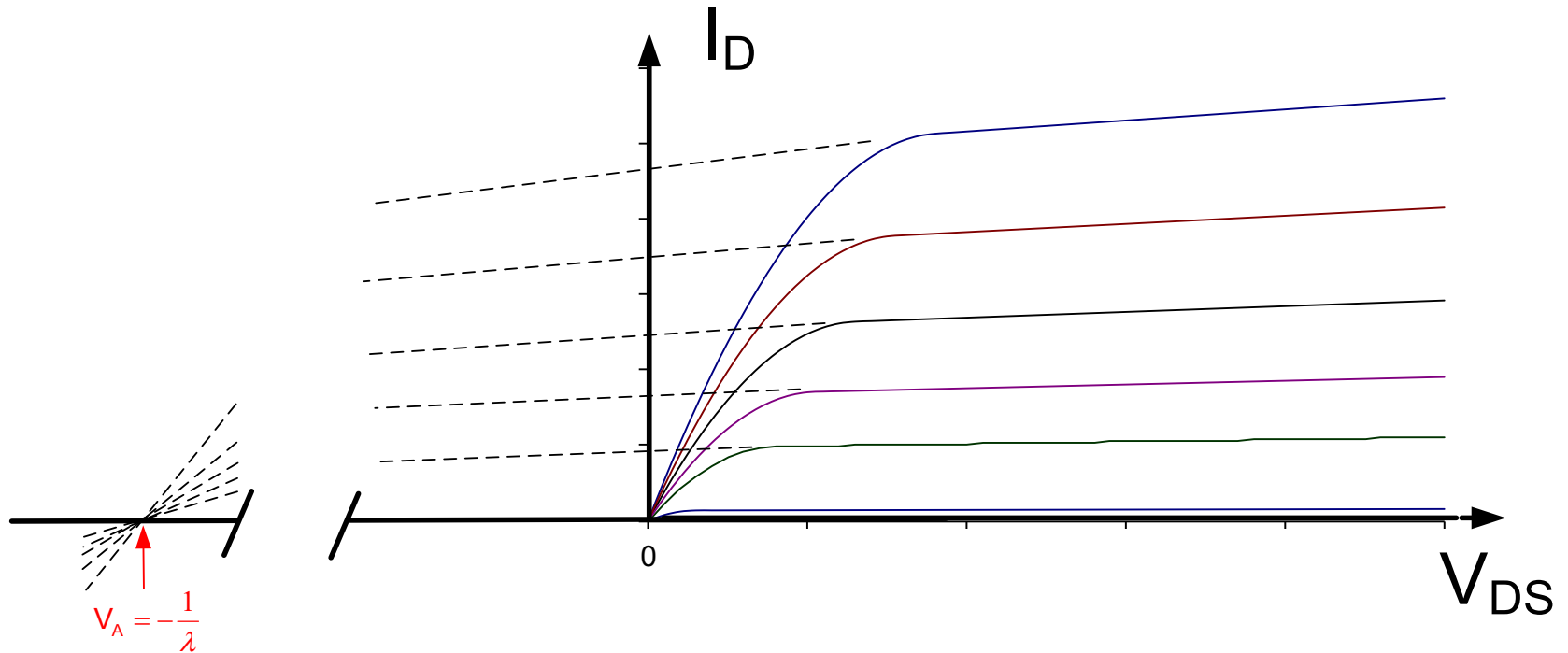
Switch-Level Models

Simple square-law Model



Voltage Gain
Input/Output Relationship ?

Model Extensions

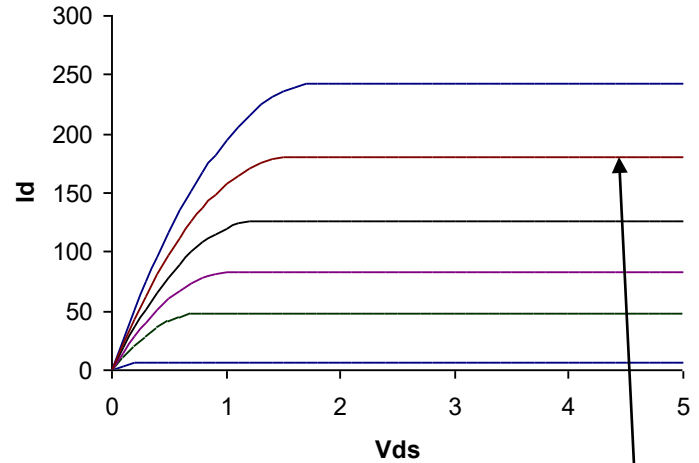


Projections intersect $-V_{DS}$ axis at same point, termed Early Voltage

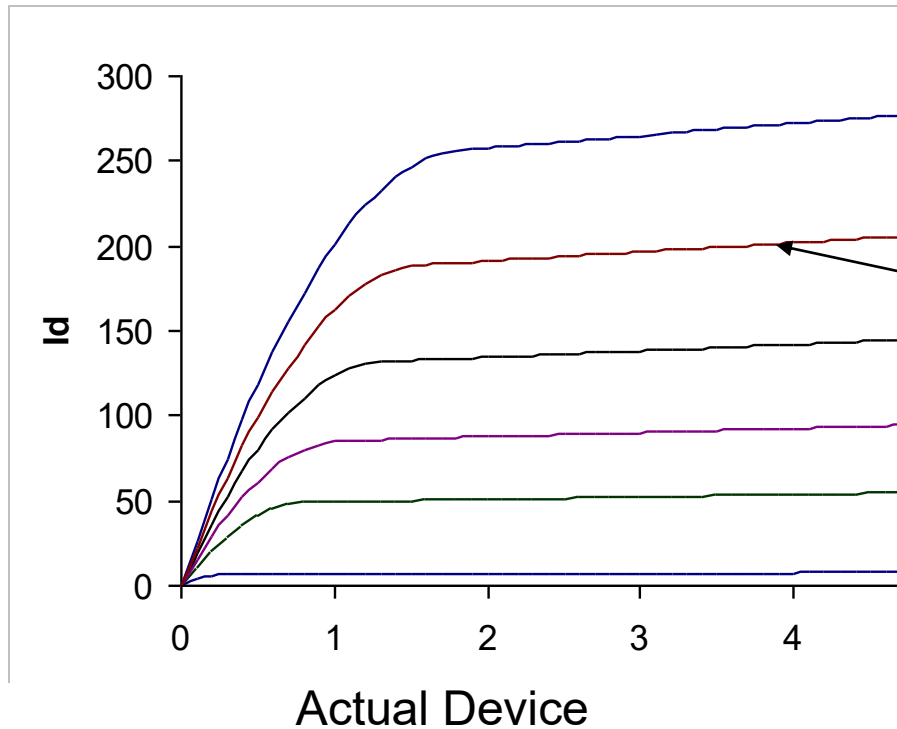
Typical values from -20V to -200V

Usually use parameter λ instead of V_A in MOS model

Model Extensions

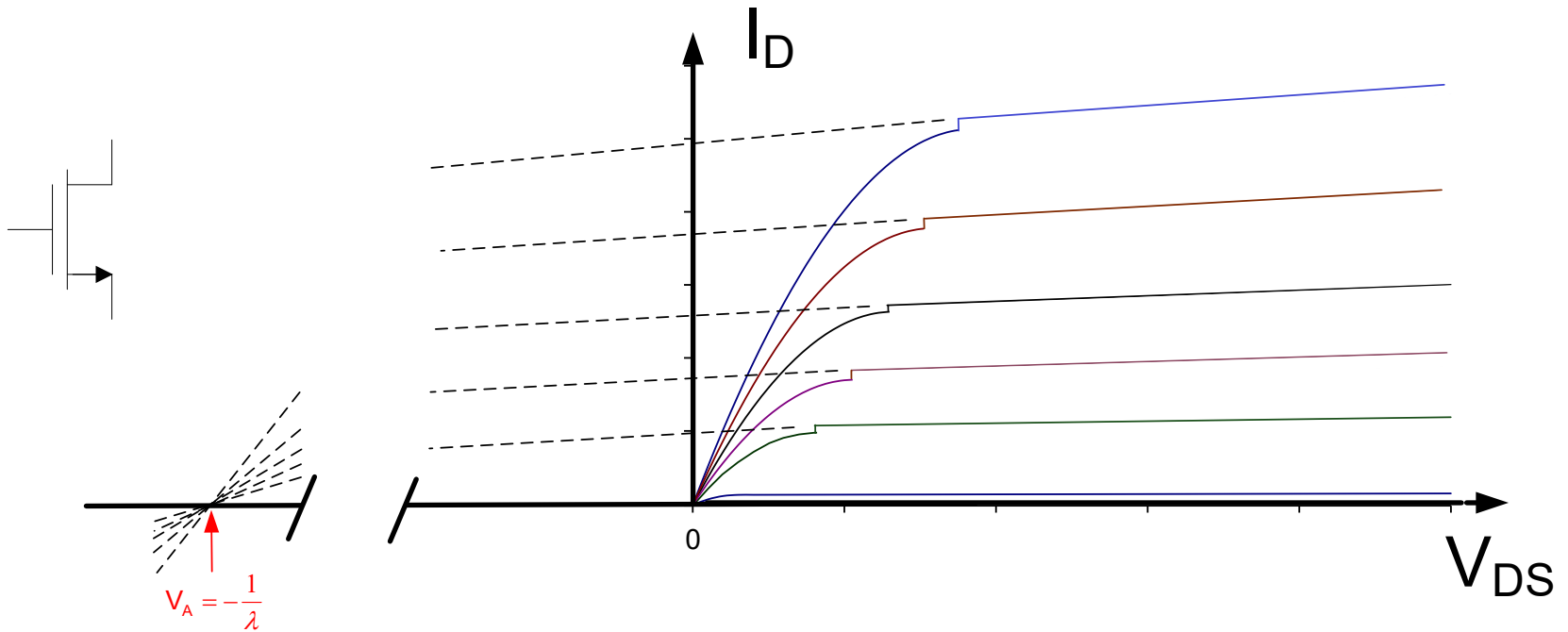


Existing Model



Slope is not 0

Model Extensions

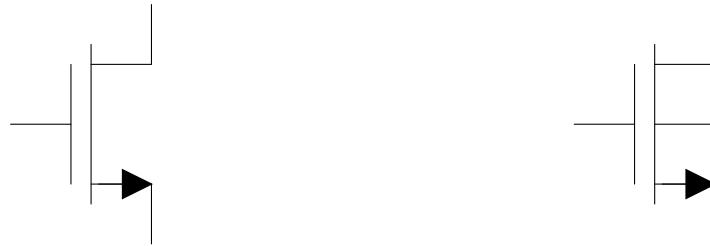


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_T)^2 \cdot (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

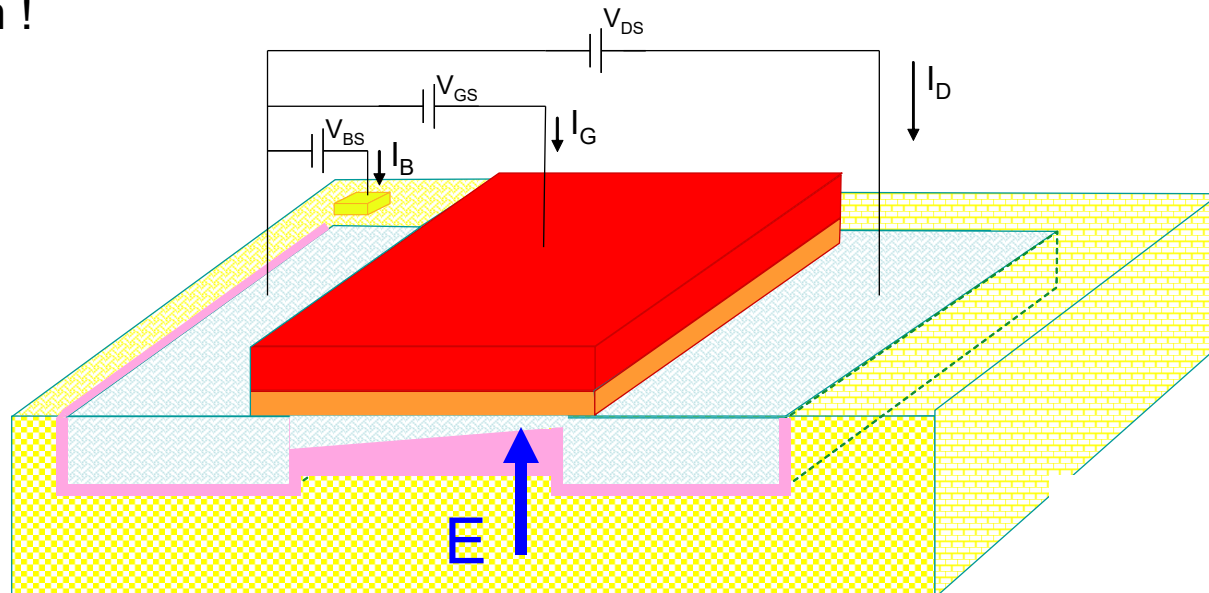
Note: This introduces small discontinuity in model at SAT/Triode transition

Further Model Extensions

Existing model does not depend upon the bulk voltage !



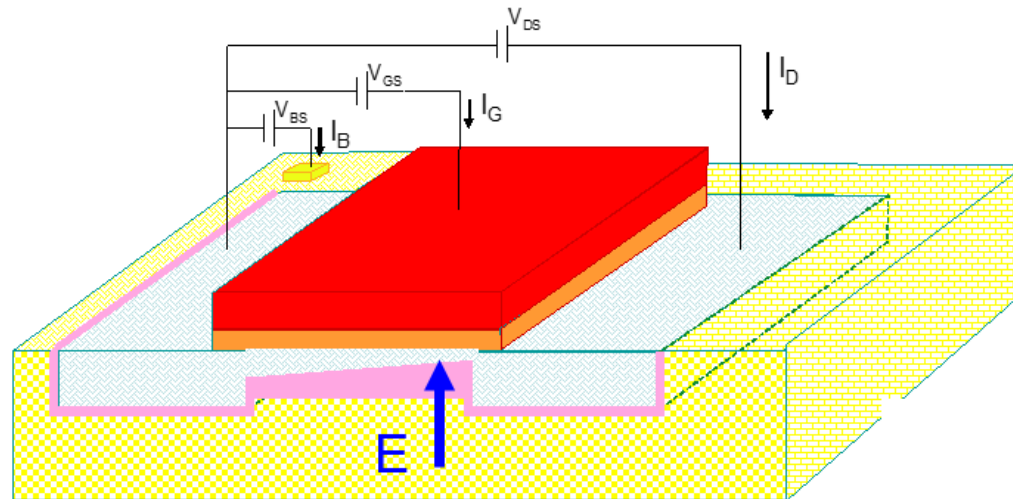
Observe that changing the bulk voltage will change the electric field in the channel region !



Further Model Extensions

Existing model does not depend upon the bulk voltage !

Observe that changing the bulk voltage will change the electric field in the channel region !



Changing the bulk voltage will change the thickness of the inversion layer

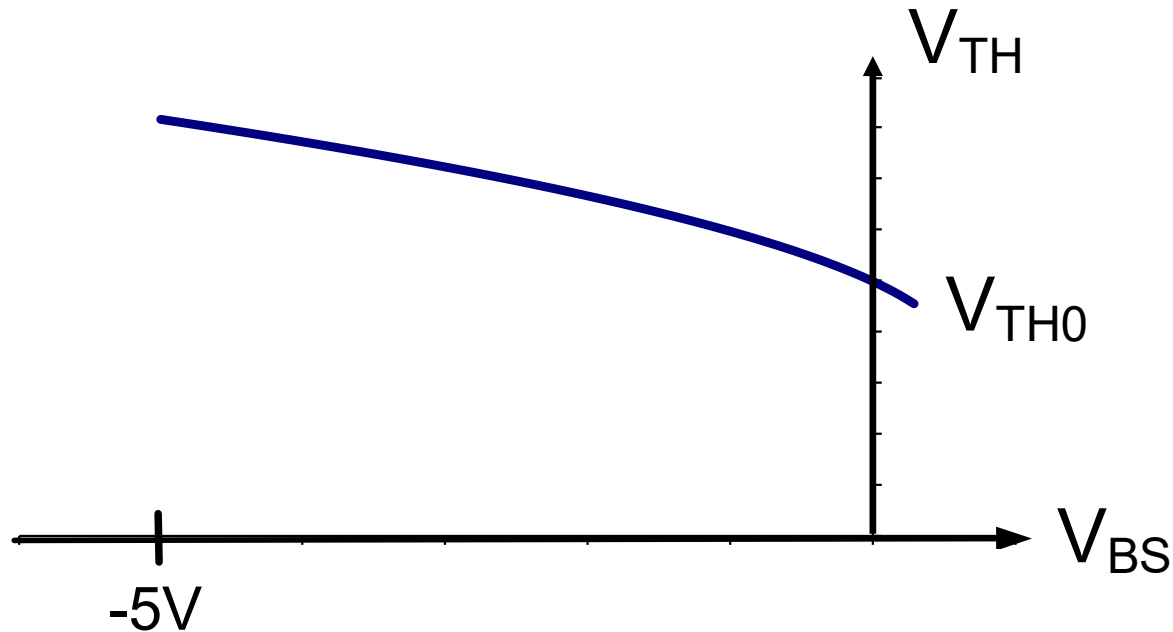
Changing the bulk voltage will change the threshold voltage of the device

$$V_T = V_{T0} + \gamma(\sqrt{\phi - V_{BS}} - \sqrt{\phi})$$

Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \cong 0.4V^{1/2} \quad \phi \cong 0.6V$$

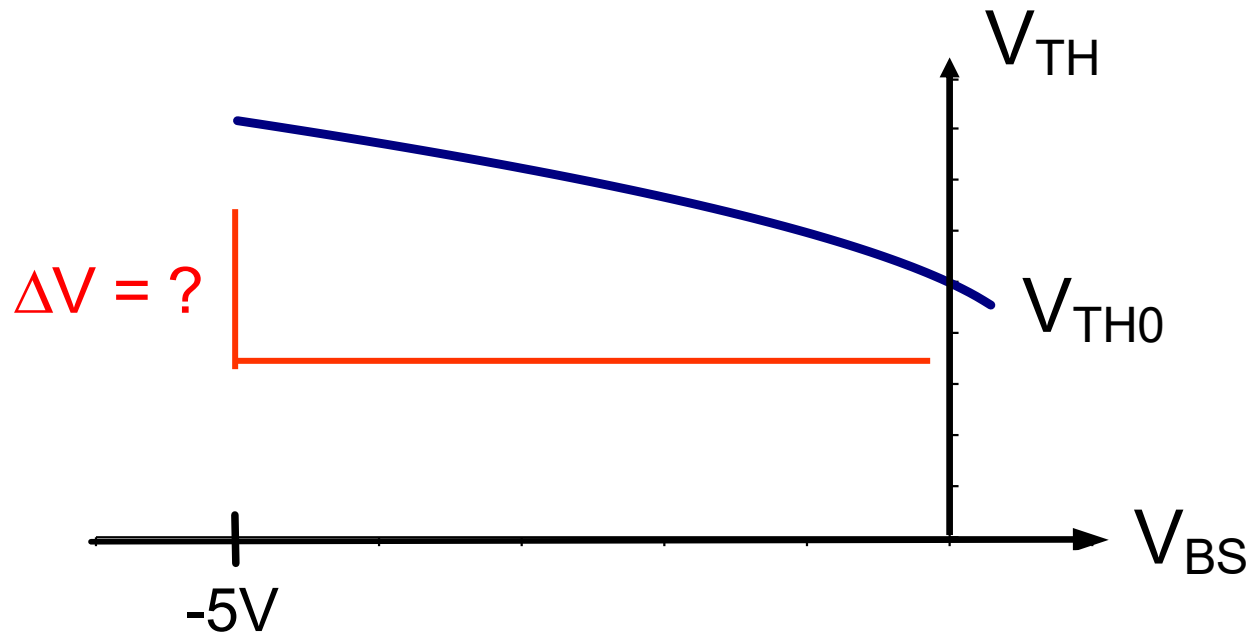


- Bulk-Diffusion Generally Reverse Biased ($V_{BS} < 0$ or at least $V_{BS} < 0.3V$) for n-channel
- Shift in threshold voltage with bulk voltage can be substantial
- Often $V_{BS} = 0$

Typical Bulk Effects on Threshold Voltage for n-channel Devices

$$V_{TH} = V_{TH0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \cong 0.4V^{1/2} \quad \phi \cong 0.6V$$



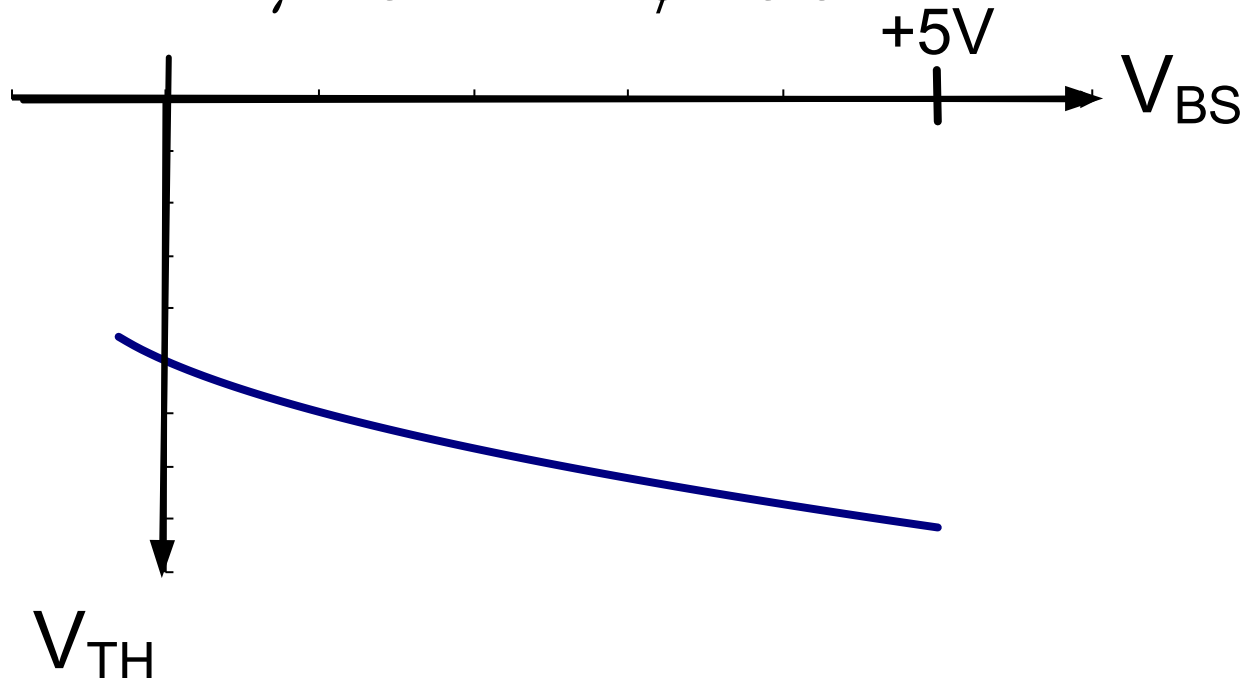
$$\Delta V = V_{TH} - V_{TH0} = \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

$$\Delta V \cong 0.4 \left(\sqrt{0.6V - (-5V)} - \sqrt{0.6} \right) \cong 0.64V$$

Typical Bulk Effects on Threshold Voltage for p-channel Devices

$$V_{TH} = V_{TH0} - \gamma \left(\sqrt{\phi + V_{BS}} - \sqrt{\phi} \right)$$

$$\gamma \cong 0.4V^{1/2} \quad \phi \cong 0.6V$$

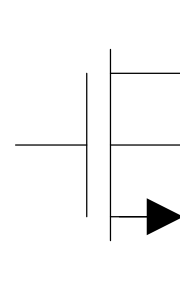


- Bulk-Diffusion Generally Reverse Biased ($V_{BS} > 0$ or at least $V_{BS} > -0.3V$) for p-channel
- Same functional form as for n-channel but $V_{TH0} < 0$
- Magnitude of threshold voltage increases with magnitude of reverse bias

Model Extension Summary

$$I_G = 0$$

$$I_B = 0$$

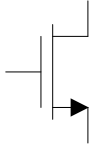


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \cdot (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

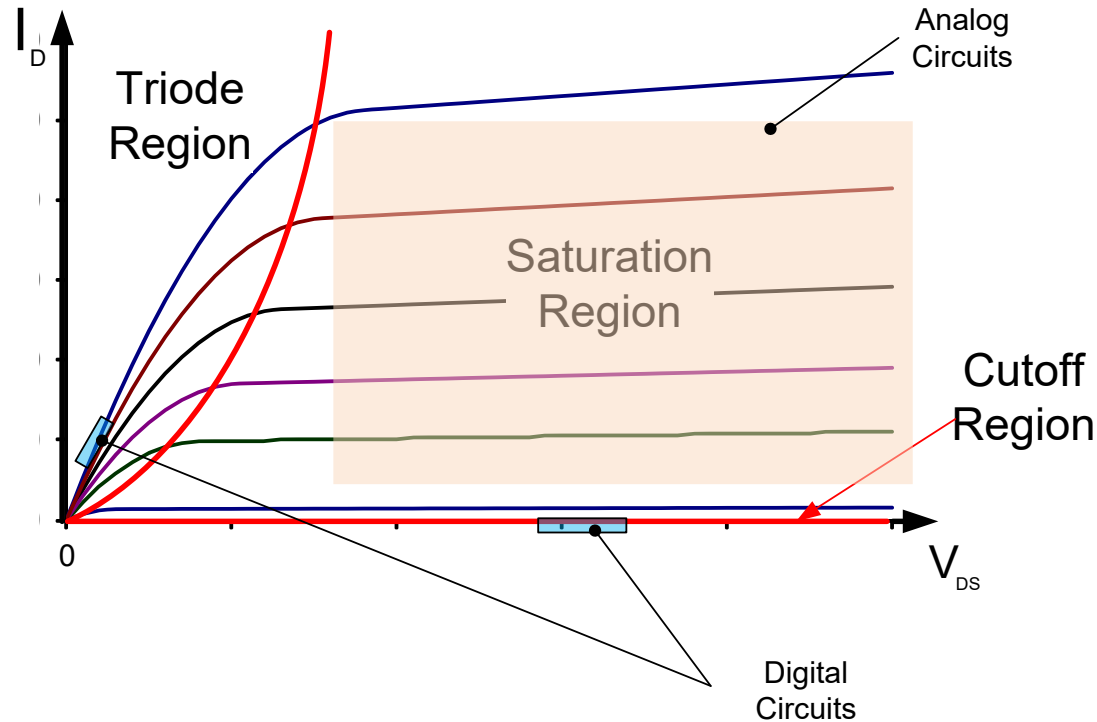
$$V_T = V_{T0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

Model Parameters : $\{\mu, C_{ox}, V_{T0}, \phi, \gamma, \lambda\}$

Design Parameters : $\{W, L\}$ but only one degree of freedom W/L



Operation Regions by Applications



Most analog circuits operate in the saturation region

(basic VVR operates in triode and is an exception)

Most digital circuits operate in triode and cutoff regions and switch between these two with Boolean inputs

Model Extension (short devices)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{OX} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{OX} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

As the channel length becomes very short, velocity saturation will occur in the channel and this will occur with electric fields around $2V/u$. So, if a gate length is around $1u$, then voltages up to $2V$ can be applied without velocity saturation. But, if gate length decreases and voltages are kept high, velocity saturation will occur

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{OX} \frac{W}{L} (V_{GS} - V_T)^\alpha V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^\alpha \\ \theta_2 \mu C_{OX} \frac{W}{L} (V_{GS} - V_T)^\alpha & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^\alpha \end{cases}$$

α is the velocity saturation index, $2 \geq \alpha \geq 1$

Model Extension (short devices)

(n-channel device)

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^\alpha V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^\alpha \\ \theta_2 \mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^\alpha & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^\alpha \end{cases}$$

α is the velocity saturation index, $2 \geq \alpha \geq 1$

No longer a square-law model (some term it an α -power or α -law model)

For long devices, $\alpha=2$

Channel length modulation (λ) and bulk effects can be added to the velocity Saturation as well

Degrading of α is not an attractive limitation of the MOSFET

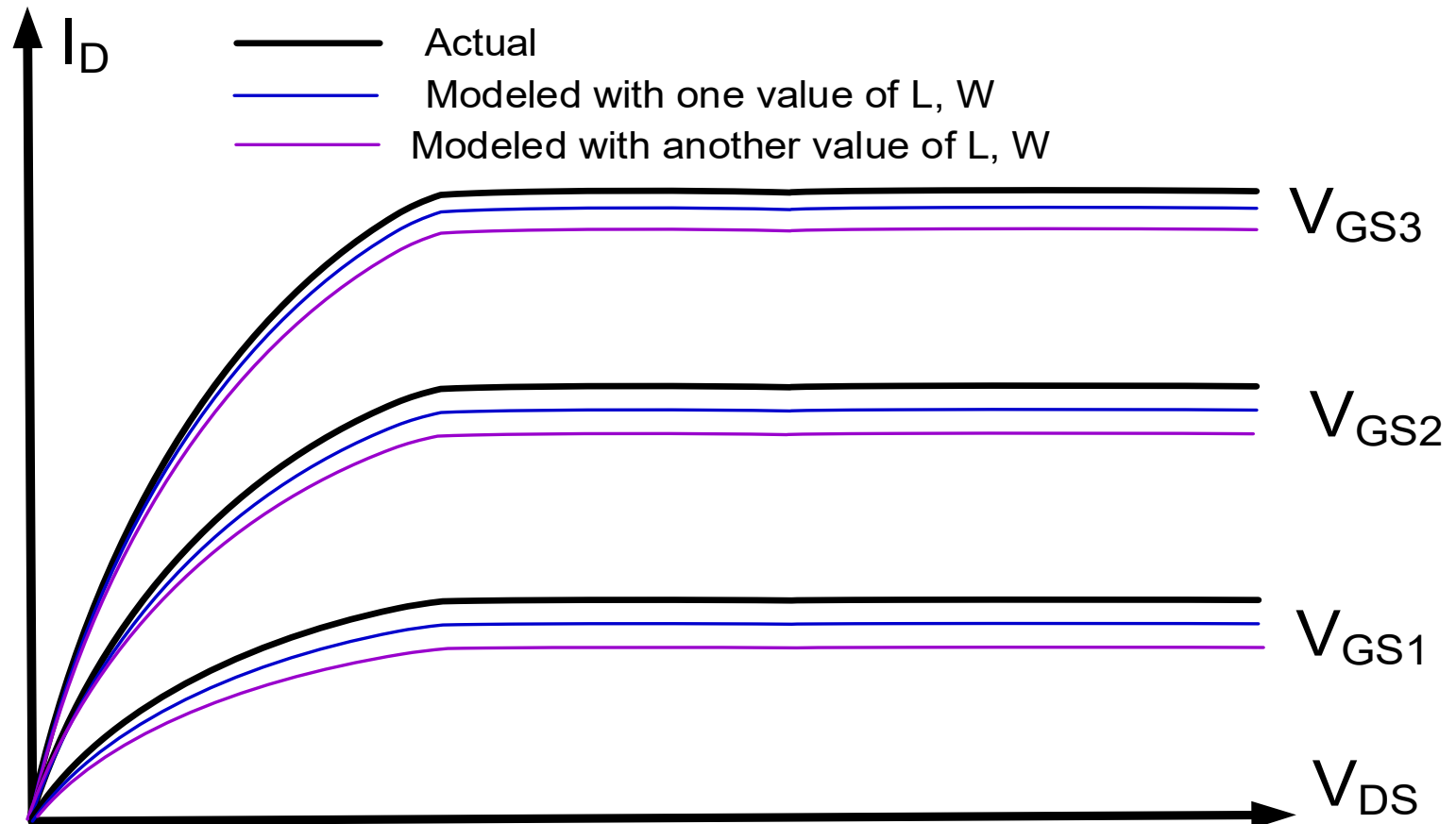
Be aware of existence but of little use !

(too complicated for analytical calculations, not accurate enough for simulations)

Model Extension (BSIM model)

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27          LEVEL   = 49
+XJ      = 1.5E-7      NCH     = 1.7E17      TOX     = 1.42E-8
+K1      = 0.8976376   K2     = -0.09255    VTH0    = 0.629035
+K3B     = -8.2369696  W0     = 1.041146E-8 K3      = 24.0984767
+DVT0W   = 0          DVT1W  = 0          NLX     = 1E-9
+DVT0    = 2.7123969  DVT1   = 0.4232931  DVT2W   = 0
+U0      = 451.2322004 UA     = 3.091785E-13 DVT2    = -0.1403765
+UC      = 1.22401E-11 VSAT   = 1.715884E5   UB     = 1.702517E-18
+AGS     = 0.130484   B0     = 2.446405E-6 A0      = 0.6580918
+KETA    = -3.043349E-3 A1     = 8.18159E-7  B1     = 5E-6
+RDSW    = 1.367055E3 PRWG   = 0.0328586  A2     = 0.3363058
+WR      = 1          WINT   = 2.443677E-7 PRWB    = 0.0104806
+XL      = 1E-7      XW     = 0          LINT   = 6.999776E-8
+DWB     = 3.676235E-8 VOFF   = -1.493503E-4 DWG     = -1.256454E-8
+CIT     = 0          CDSC   = 2.4E-4      NFACTOR = 1.0354201
+CDSCB   = 0          ETA0   = 2.342963E-3 CDSCD   = 0
+DSUB    = 0.0764123 PCLM   = 2.5941582  ETAB   = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505  PDIBLC1 = 0.8187825
+PSCBE1  = 6.611774E8 PSCBE2 = 3.238266E-4 DROUT   = 0.9919348
                                     PVAG   = 0
+PRT     = 0          UTE    = -1.5       KT1     = -0.11
+KT1L    = 0          KT2    = 0.022      UA1     = 4.31E-9
+UB1     = -7.61E-18 UC1     = -5.6E-11  AT      = 3.3E4
+WL      = 0          WLN    = 1         WW      = 0
+WWN     = 1          WWL    = 0         LL      = 0
+LLN     = 1          LW     = 0         LWN    = 1
+LWL     = 0          CAPMOD = 2         XPART   = 0.5
+CGDO    = 2.32E-10  CGSO   = 2.32E-10  CGBO   = 1E-9
+CJ      = 4.282017E-4 PB      = 0.9317787 MJ      = 0.4495867
+CJSW    = 3.034055E-10 PBSW   = 0.8       MJSW   = 0.1713852
+CJSWG   = 1.64E-10  PBSWG  = 0.8       MJSWG  = 0.1713852
+CF      = 0          PVTH0  = 0.0520855 PRDSW  = 112.8875816
+PK2     = -0.0289036 WKETA  = -0.0237483 LKETA  = 1.728324E-3
*)
*
```

Model Errors with Different W/L Values



Binning models can improve model accuracy

BSIM Binning Model

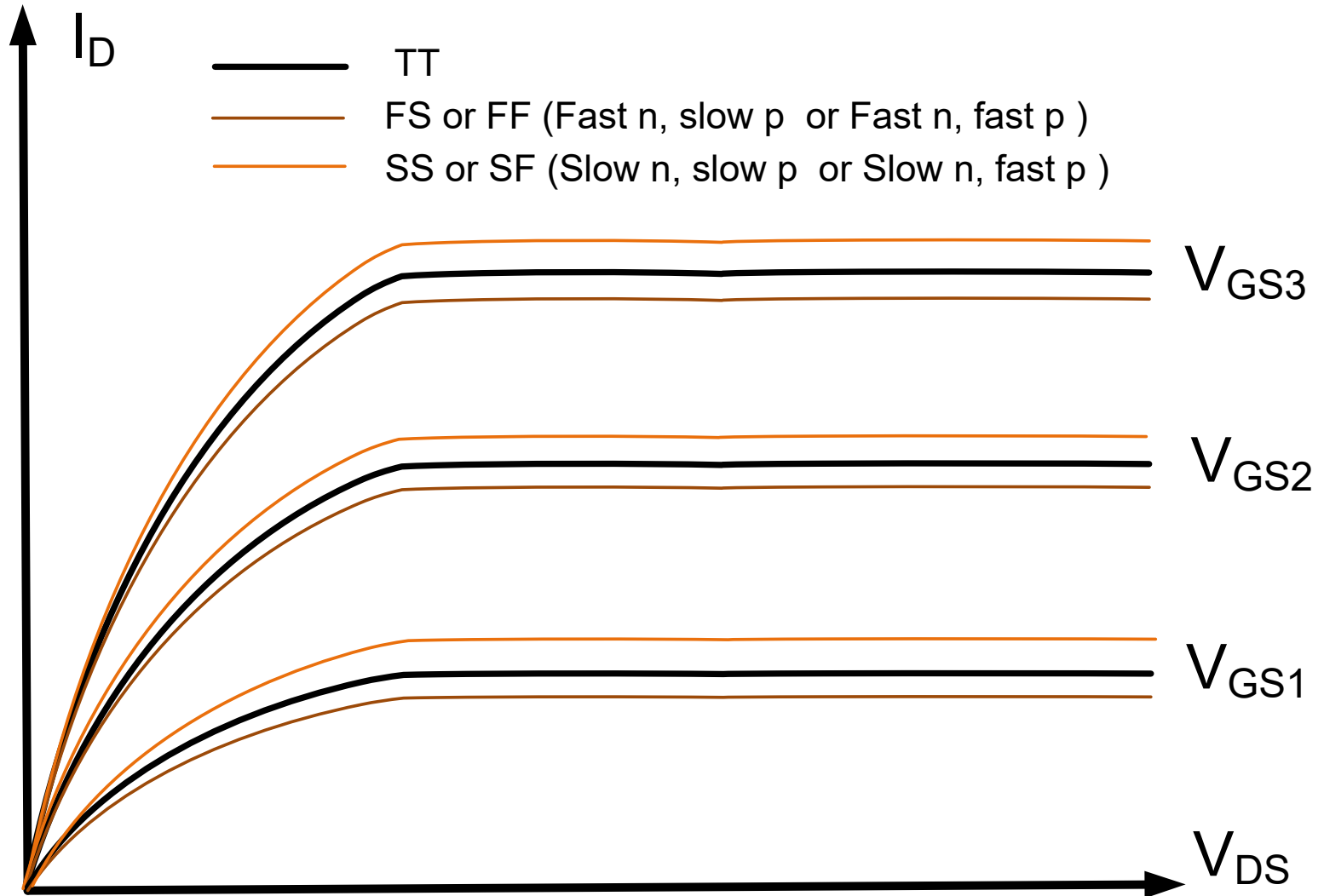
- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27          LEVEL   = 49
+XJ      = 1.5E-7      NCH     = 1.7E17      TOX     = 1.42E-8
+K1      = 0.8976376   K2     = -0.09255    VTH0    = 0.629035
+K3B     = -8.2369696  W0     = 1.041146E-8 K3      = 24.0984767
+DVT0W   = 0          DVT1W  = 0          NLX     = 1E-9
+DVT0    = 2.7123969  DVT1   = 0.4232931  DVT2W   = 0
+U0      = 451.2322004 UA     = 3.091785E-13 DVT2    = -0.1403765
+UC      = 1.22401E-11 VSAT   = 1.715884E5   UB     = 1.702517E-18
+AGS     = 0.130484   B0     = 2.446405E-6 A0      = 0.6580918
+KETA    = -3.043349E-3 A1     = 8.18159E-7  B1     = 5E-6
+RDSW    = 1.367055E3 PRWG   = 0.0328586  A2     = 0.3363058
+WR      = 1          WINT   = 2.443677E-7 PRWB    = 0.0104806
+XL      = 1E-7       XW     = 0          LINT    = 6.999776E-8
+DWB     = 3.676235E-8 VOFF   = -1.493503E-4 DWG     = -1.256454E-8
+CIT     = 0          CDSC   = 2.4E-4      NFACTOR = 1.0354201
+CDSCB   = 0          ETA0   = 2.342963E-3 CDSCD   = 0
+DSUB    = 0.0764123 PCLM   = 2.5941582  ETAB    = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505  PDIBLC1 = 0.8187825
+PSCBE1  = 6.611774E8 PSCBE2 = 3.238266E-4 DROUT   = 0.9919348
                                     PVAG   = 0
+PRT     = 0          UTE    = -1.5       KT1     = -0.11
+KT1L    = 0          KT2    = 0.022      UA1     = 4.31E-9
+UB1     = -7.61E-18 UC1     = -5.6E-11  AT      = 3.3E4
+WL      = 0          WLN    = 1         WW      = 0
+WWN     = 1          WWL    = 0         LL      = 0
+LLN     = 1          LW     = 0         LWN     = 1
+LWL     = 0          CAPMOD = 2         XPART   = 0.5
+CGDO    = 2.32E-10  CGSO   = 2.32E-10  CGBO    = 1E-9
+CJ      = 4.282017E-4 PB      = 0.9317787 MJ      = 0.4495867
+CJSW    = 3.034055E-10 PBSW   = 0.8       MJSW    = 0.1713852
+CJSWG   = 1.64E-10  PBSWG  = 0.8       MJSWG   = 0.1713852
+CF      = 0          PVTH0  = 0.0520855 PRDSW   = 112.8875816
+PK2     = -0.0289036 WKETA   = -0.0237483 LKETA   = 1.728324E-3 )
*
```

With 32 bins, this model has 3040 model parameters !

Model Changes with Process Variations

(n-ch characteristics shown)



Corner models can improve model accuracy

BSIM Corner Models with Binning

- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS

- bin on device sizes

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM = 27          LEVEL = 49
+XJ = 1.5E-7          NCH = 1.7E17        TOX = 1.42E-8
+K1 = 0.8976376      K2 = -0.09255        VTH0 = 0.629035
+K3B = -8.2369696    W0 = 1.041146E-8      K3 = 24.0984767
+DVT0W = 0           DVT1W = 0          NLX = 1E-9
+DVT0 = 2.7123969    DVT1 = 0.4232931        DVT2W = 0
+U0 = 451.2322004    UA = 3.091785E-13     DVT2 = -0.1403765
+UC = 1.22401E-11    VSAT = 1.715884E5      UB = 1.702517E-18
+AGS = 0.130484      B0 = 2.446405E-6       A0 = 0.6580918
+KETA = -3.043349E-3 A1 = 8.18159E-7        B1 = 5E-6
+RDSW = 1.367055E3   PRWG = 0.0328586       A2 = 0.3363058
+WR = 1              WINT = 2.443677E-7    PRWB = 0.0104806
+XL = 1E-7           XW = 0                 LINT = 6.999776E-8
+DWB = 3.676235E-8   VOFF = -1.493503E-4   DWG = -1.256454E-8
+CIT = 0             CDSC = 2.4E-4          NFACTOR = 1.0354201
+CDSCB = 0           ETA0 = 2.342963E-3    CDSCD = 0
+DSUB = 0.0764123    PCIM = 2.5941582      ETAB = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505   PDIBLC1 = 0.8187825
+PSCBE1 = 6.611774E8 PSCBE2 = 3.238266E-4  DROUT = 0.9919348
+DPR.TA = 0.01       RSH = 83.5            PVAG = 0
+PRT = 0             UTE = -1.5            MORMOD = 1
+KT1L = 0            KT2 = 0.022           KT1 = -0.11
+UB1 = -7.61E-18     UC1 = -5.6E-11        UA1 = 4.31E-9
+WL = 0              WLN = 1               AT = 3.3E4
+WWN = 1             WWL = 0               WW = 0
+LLN = 1             LW = 0                LL = 0
+LWL = 0             CAPMOD = 2            LWN = 1
+CGDO = 2.32E-10     CGSO = 2.32E-10       XPART = 0.5
+CJ = 4.282017E-4    PB = 0.9317787        CGBO = 1E-9
+CJSW = 3.034055E-10 PBSW = 0.8             MJ = 0.4495867
+CJSWG = 1.64E-10    PBSWG = 0.8           MJSW = 0.1713852
+CF = 0              PVTH0 = 0.0520855    MJSWG = 0.1713852
+PK2 = -0.0289036   WKETA = -0.0237483    PRDSW = 112.8875816
                    LKETA = 1.728324E-3
*)
```

With 32 size bins and 4 corners, this model has 15,200 model parameters !

How many models of the MOSFET do we have?

Switch-level model (2)

Square-law model

Square-law model (with λ and bulk additions)

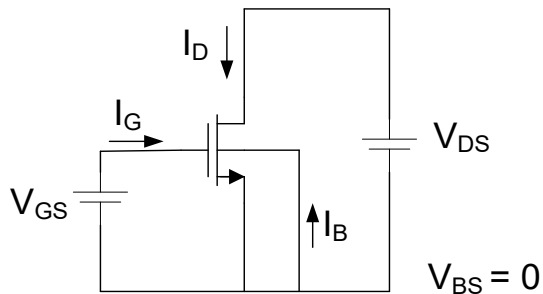
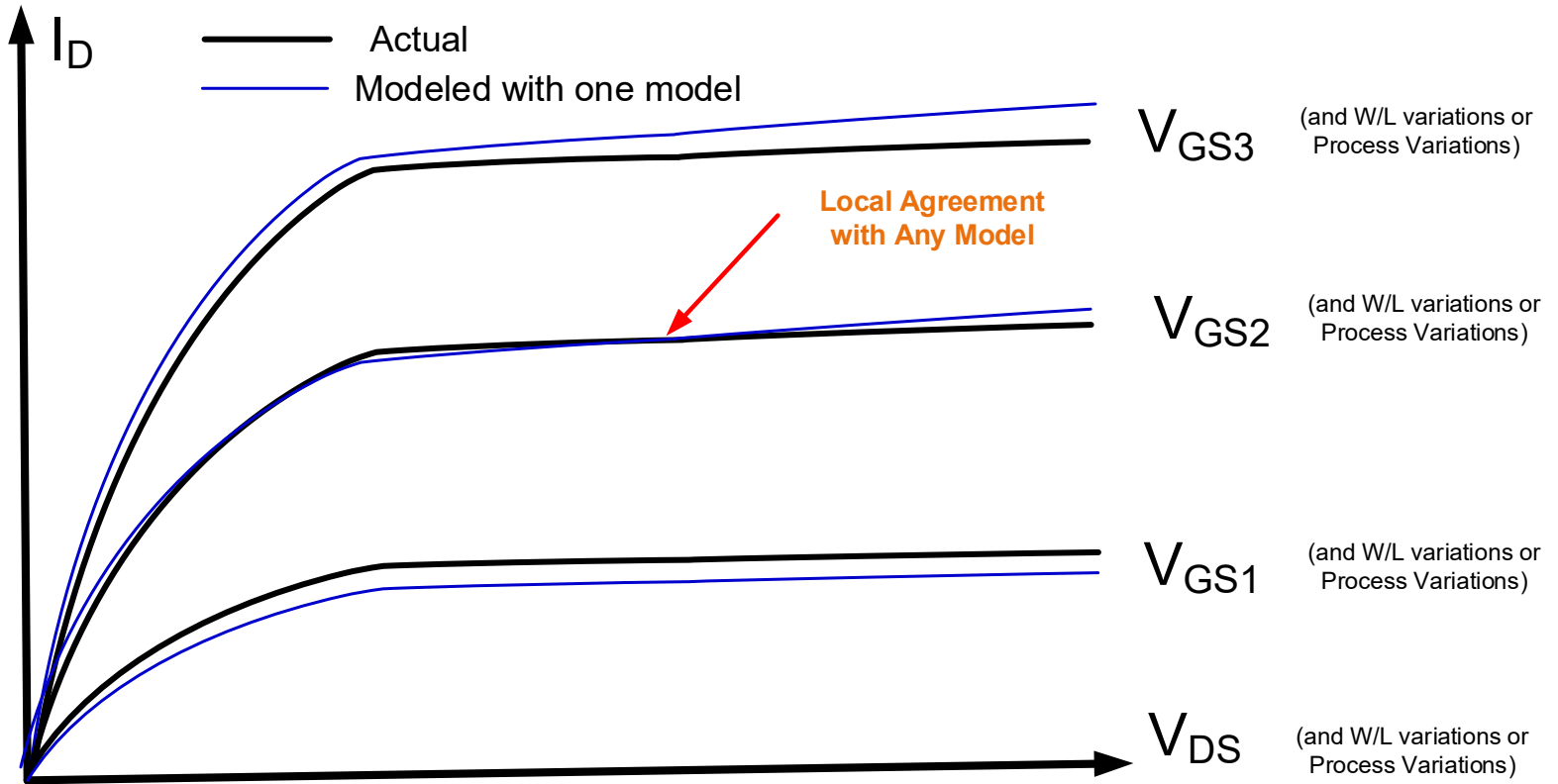
α -law model (with λ and bulk additions)

BSIM model

BSIM model (with binning extensions)

BSIM model (with binning extensions and process corners)

The Modeling Challenge



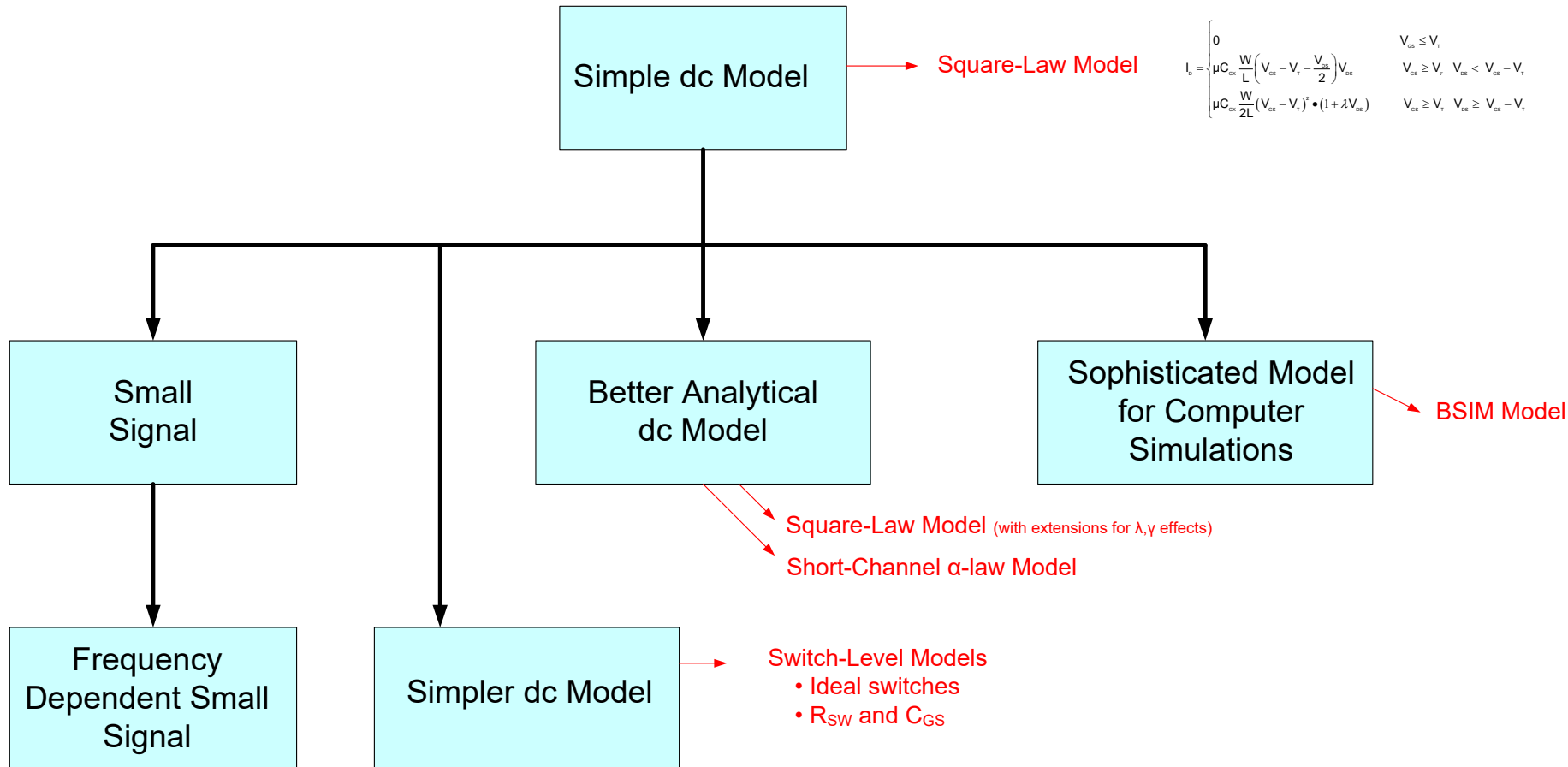
$$I_D = f_1(V_{GS}, V_{DS})$$

$$I_G = f_2(V_{GS}, V_{DS})$$

$$I_B = f_3(V_{GS}, V_{DS})$$

Difficult to obtain analytical functions that accurately fit actual devices over bias, size, and process variations

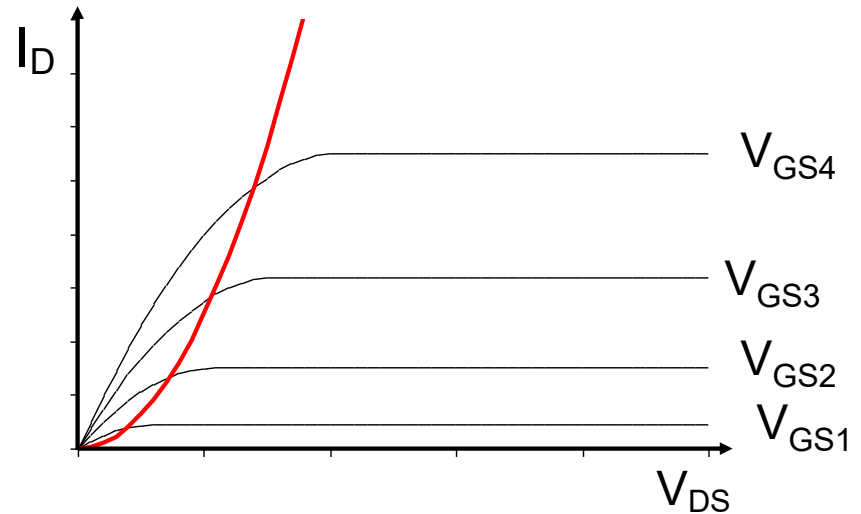
Model Status



In the next few slides, the models we have developed will be listed and reviewed

- Square-law Model
- Switch-level Models
- Extended Square-law model
- Short-channel model
- BSIM Model
- BSIM Binning Model
- Corner Models

Square-Law Model

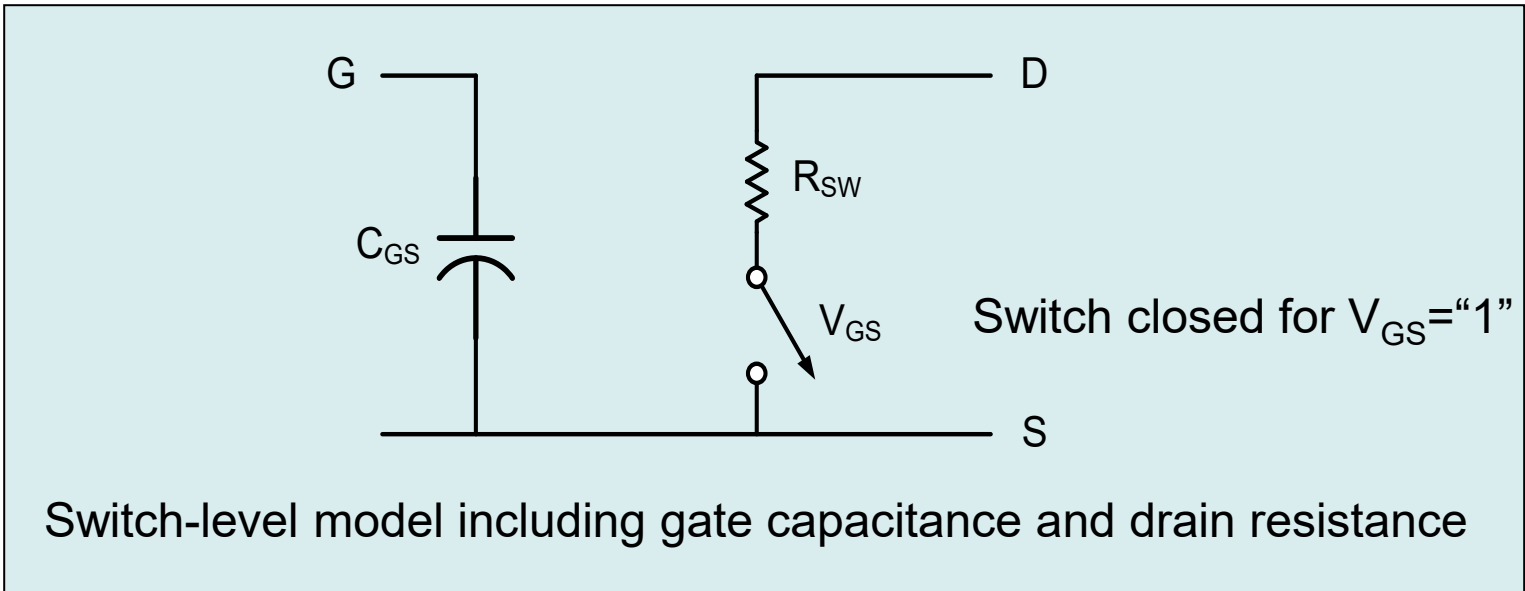
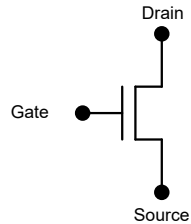


$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

Model Parameters : $\{\mu, C_{OX}, V_{T0}\}$

Design Parameters : $\{W, L\}$ but only one degree of freedom W/L

Switch-Level Models



C_{GS} and R_{SW} dependent upon device sizes and process

For minimum-sized devices in a 0.5u process

$$C_{GS} \cong 1.5\text{fF} \quad R_{sw} \cong \left. \begin{array}{l} 2\text{K}\Omega \text{ n-channel} \\ 6\text{K}\Omega \text{ p-channel} \end{array} \right\}$$

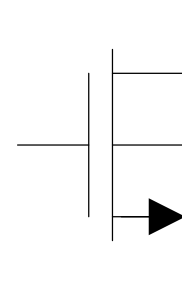
Considerable emphasis will be placed upon device sizing to manage C_{GS} and R_{SW}

Model Parameters : $\{C_{GS}, R_{SW}\}$

Extended Square-Law Model

$$I_G = 0$$

$$I_B = 0$$



$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \mu C_{ox} \frac{W}{L} \left(V_{GS} - V_T - \frac{V_{DS}}{2} \right) V_{DS} & V_{GS} \geq V_T \quad V_{DS} < V_{GS} - V_T \\ \mu C_{ox} \frac{W}{2L} (V_{GS} - V_T)^2 \cdot (1 + \lambda V_{DS}) & V_{GS} \geq V_T \quad V_{DS} \geq V_{GS} - V_T \end{cases}$$

$$V_T = V_{T0} + \gamma \left(\sqrt{\phi - V_{BS}} - \sqrt{\phi} \right)$$

Model Parameters : $\{\mu, C_{ox}, V_{T0}, \phi, \gamma, \lambda\}$

Design Parameters : $\{W, L\}$ but only one degree of freedom W/L

Short-Channel Model

$$I_D = \begin{cases} 0 & V_{GS} \leq V_T \\ \frac{\theta_2}{\theta_1} \mu C_{OX} \frac{W}{L} (V_{GS} - V_T)^{\frac{\alpha}{2}} V_{DS} & V_{GS} \geq V_T \quad V_{DS} < \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \\ \theta_2 \mu C_{OX} \frac{W}{L} (V_{GS} - V_T)^\alpha & V_{GS} \geq V_T \quad V_{DS} \geq \theta_1 (V_{GS} - V_T)^{\frac{\alpha}{2}} \end{cases}$$

α is the velocity saturation index, $2 \geq \alpha \geq 1$

Channel length modulation (λ) and bulk effects can be added to the velocity Saturation as well

BSIM model

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM    = 27          TOX      = 1.42E-8
+XJ      = 1.5E-7      NCH     = 1.7E17      VTH0    = 0.629035
+K1      = 0.8976376  K2     = -0.09255    K3       = 24.0984767
+K3B     = -8.2369696 W0     = 1.041146E-8 NLX      = 1E-9
+DVT0W   = 0          DVT1W  = 0          DVT2W   = 0
+DVT0    = 2.7123969 DVT1   = 0.4232931 DVT2    = -0.1403765
+U0      = 451.2322004 UA     = 3.091785E-13 UB      = 1.702517E-18
+UC      = 1.22401E-11 VSAT    = 1.715884E5  A0      = 0.6580918
+AGS     = 0.130484   B0     = 2.446405E-6 B1      = 5E-6
+KETA    = -3.043349E-3 A1     = 8.18159E-7  A2      = 0.3363058
+RDSW    = 1.367055E3 PRWG    = 0.0328586  PRWB    = 0.0104806
+WR      = 1          WINT   = 2.443677E-7 LINT    = 6.999776E-8
+XL      = 1E-7      XW     = 0          DWG     = -1.256454E-8
+DWB     = 3.676235E-8 VOFF   = -1.493503E-4 NFACTOR = 1.0354201
+CIT     = 0          CDSC   = 2.4E-4      CDSCD   = 0
+CDSCB   = 0          ETA0   = 2.342963E-3 ETAB    = -1.5324E-4
+DSUB    = 0.0764123 PCLM   = 2.5941582  PDIBLC1 = 0.8187825
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505  DROUT   = 0.9919348
+PSCBE1  = 6.611774E8 PSCBE2 = 3.238266E-4 PVAG    = 0

+PRT     = 0          UTE    = -1.5       KT1     = -0.11
+KT1L    = 0          KT2    = 0.022     UA1     = 4.31E-9
+UB1     = -7.61E-18 UC1     = -5.6E-11  AT      = 3.3E4
+WL      = 0          WLN    = 1         WW      = 0
+WWN     = 1          WWL    = 0         LL      = 0
+LLN     = 1          LW     = 0         LWN    = 1
+LWL     = 0          CAPMOD = 2         XPART   = 0.5
+CGDO    = 2.32E-10  CGSO   = 2.32E-10  CGBO   = 1E-9
+CJ      = 4.282017E-4 PB      = 0.9317787 MJ      = 0.4495867
+CJSW    = 3.034055E-10 PBSW   = 0.8       MJSW   = 0.1713852
+CJSWG   = 1.64E-10  PBSWG  = 0.8       MJSWG  = 0.1713852
+CF      = 0          PVTH0  = 0.0520855 PRDSW  = 112.8875816
+PK2     = -0.0289036 WKETA  = -0.0237483 LKETA  = 1.728324E-3 )
*
```

Note this model has 95 model parameters !

BSIM Binning Model

- Bin on device sizes
- multiple BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM = 27          LEVEL = 49
+XJ = 1.5E-7          NCH = 1.7E17        TOX = 1.42E-8
+K1 = 0.8976376      K2 = -0.09255        VTH0 = 0.629035
+K3B = -8.2369696    W0 = 1.041146E-8       K3 = 24.0984767
+DVT0W = 0           DVT1W = 0           NLX = 1E-9
+DVT0 = 2.7123969    DVT1 = 0.4232931       DVT2W = 0
+U0 = 451.2322004    UA = 3.091785E-13     DVT2 = -0.1403765
+UC = 1.22401E-11    VSAT = 1.715884E5      UB = 1.702517E-18
+AGS = 0.130484      B0 = 2.446405E-6       A0 = 0.6580918
+KETA = -3.043349E-3 A1 = 8.18159E-7        B1 = 5E-6
+RDSW = 1.367055E3   PRWG = 0.0328586      A2 = 0.3363058
+WR = 1              WINT = 2.443677E-7    PRWB = 0.0104806
+XL = 1E-7           XW = 0                LINT = 6.999776E-8
+DWB = 3.676235E-8   VOFF = -1.493503E-4   DWG = -1.256454E-8
+CIT = 0             CDSC = 2.4E-4          NFACTOR = 1.0354201
+CDSCB = 0           ETA0 = 2.342963E-3    CDSCD = 0
+DSUB = 0.0764123    PCLM = 2.5941582      ETAB = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505  PDIBLC1 = 0.8187825
+PSCBE1 = 6.611774E8 PSCBE2 = 3.238266E-4  DROUT = 0.9919348
                    UTE = -1.5          PVAG = 0
+PRT = 0             KT2 = 0.022           KT1 = -0.11
+KT1L = 0            UC1 = -5.6E-11        UA1 = 4.31E-9
+UB1 = -7.61E-18     WLN = 1              AT = 3.3E4
+WL = 0              WWL = 0              WW = 0
+WWN = 1             LWL = 0              LL = 0
+LLN = 1             LW = 0               LWN = 1
+LWL = 0             CAPMOD = 2           XPART = 0.5
+CGDO = 2.32E-10     CGSO = 2.32E-10      CGBO = 1E-9
+CJ = 4.282017E-4    PB = 0.9317787       MJ = 0.4495867
+CJSW = 3.034055E-10 PBSW = 0.8            MJSW = 0.1713852
+CJSWG = 1.64E-10    PBSWG = 0.8          MJSWG = 0.1713852
+CF = 0              PVTH0 = 0.0520855    PRDSW = 112.8875816
+PK2 = -0.0289036   WKETA = -0.0237483   LKETA = 1.728324E-3 )
*
```

With 32 bins, this model has 3040 model parameters !

BSIM Corner Models

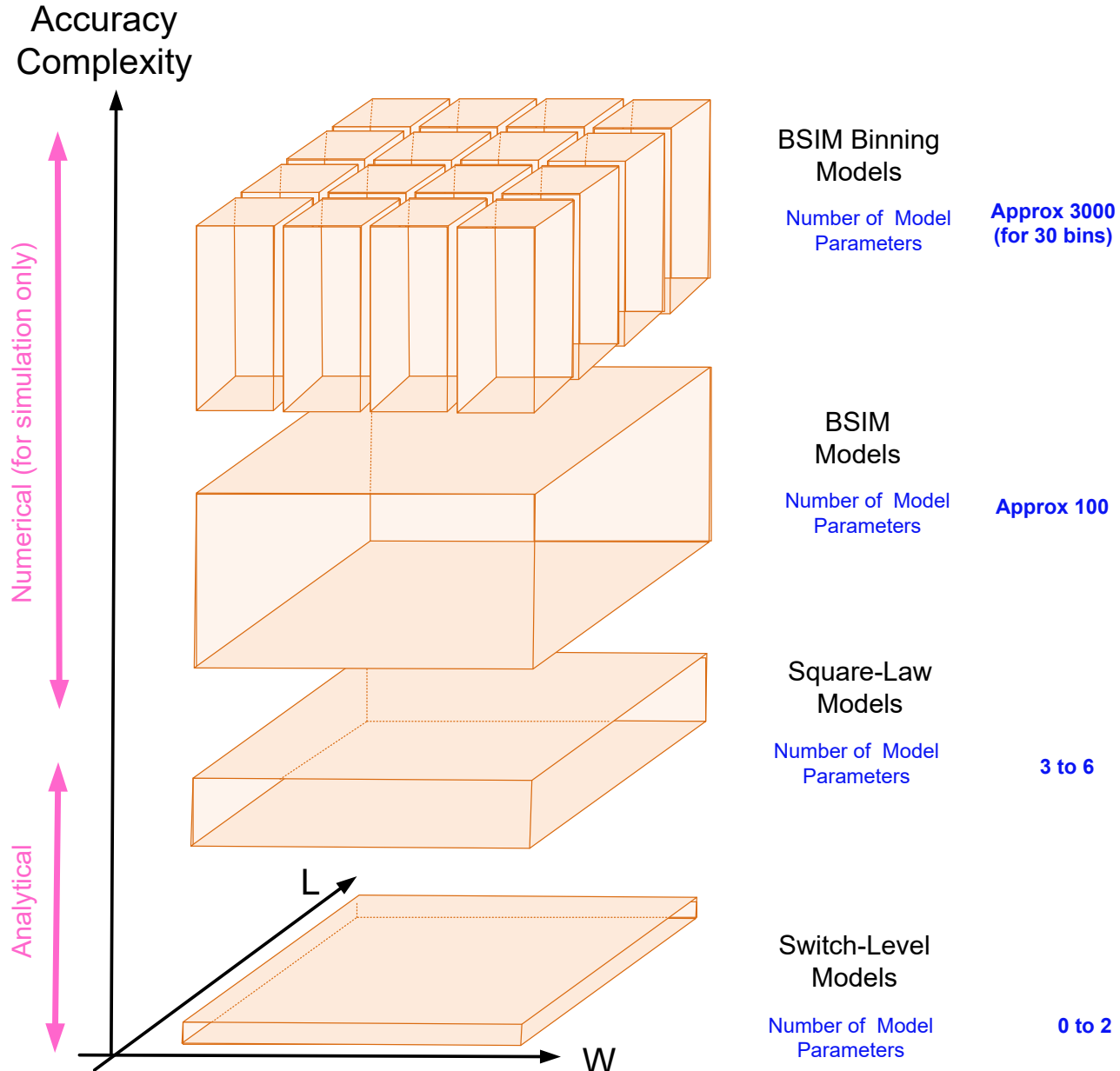
- Often 4 corners in addition to nominal TT, FF, FS, SF, and SS
- five different BSIM models !

```
.MODEL CMOSN NMOS (
+VERSION = 3.1          TNOM      = 27          LEVEL   = 49
+XJ      = 1.5E-7       NCH      = 1.7E17       TOX     = 1.42E-8
+K1      = 0.8976376    K2       = -0.09255    VTH0    = 0.629035
+K3B     = -8.2369696   W0       = 1.041146E-8 K3       = 24.0984767
+DVT0W   = 0           DVT1W   = 0           NLX     = 1E-9
+DVT0    = 2.7123969   DVT1    = 0.4232931   DVT2W   = 0
+U0      = 451.2322004  UA       = 3.091785E-13 DVT2    = -0.1403765
+UC      = 1.22401E-11  VSAT    = 1.715884E5   UB       = 1.702517E-18
+AGS     = 0.130484    B0       = 2.446405E-6  A0      = 0.6580918
+KETA    = -3.043349E-3 A1       = 8.18159E-7   B1      = 5E-6
+RDSW    = 1.367055E3  PRWG    = 0.0328586   A2      = 0.3363058
+WR      = 1           WINT    = 2.443677E-7 PRWB    = 0.0104806
+XL      = 1E-7        XW      = 0           LINT    = 6.999776E-8
+DWB     = 3.676235E-8 VOFF    = -1.493503E-4 DWG     = -1.256454E-8
+CIT      = 0          CDSC    = 2.4E-4        NFACTOR = 1.0354201
+CDSCB   = 0          ETA0    = 2.342963E-3  CDSCD   = 0
+DSUB    = 0.0764123  PCLM    = 2.5941582   ETAB    = -1.5324E-4
+PDIBLC2 = 2.366707E-3 PDIBLCB = -0.0431505   PDIBLC1 = 0.8187825
+PSCBE1  = 6.611774E8 PSCBE2  = 3.238266E-4 DROUT   = 0.9919348
+DRIFTA  = 0.01       RSH     = 83.5        PVAG    = 0
+PRT     = 0          UTE     = -1.5        MORMOD  = 1
+KT1L    = 0          KT2     = 0.022       KT1     = -0.11
+UB1     = -7.61E-18  UC1     = -5.6E-11   UA1     = 4.31E-9
+WL      = 0          WLN     = 1           AT      = 3.3E4
+WWN     = 1          WWL     = 0           WW      = 0
+LLN     = 1          LW      = 0           LL      = 0
+LWL     = 0          CAPMOD  = 2           LWN     = 1
+CGDO    = 2.32E-10   CGSO    = 2.32E-10   XPART   = 0.5
+CJ      = 4.282017E-4 PB       = 0.9317787   CGBO    = 1E-9
+CJSW    = 3.034055E-10 PBSW    = 0.8          MJ      = 0.4495867
+CJSWG   = 1.64E-10  PBSWG   = 0.8          MJSW    = 0.1713852
+CF      = 0          PVTH0   = 0.0520855   MJSWG   = 0.1713852
+PK2     = -0.0289036 WKETA   = -0.0237483  PRDSW   = 112.8875816
+                                     LKETA   = 1.728324E-3
*)
```

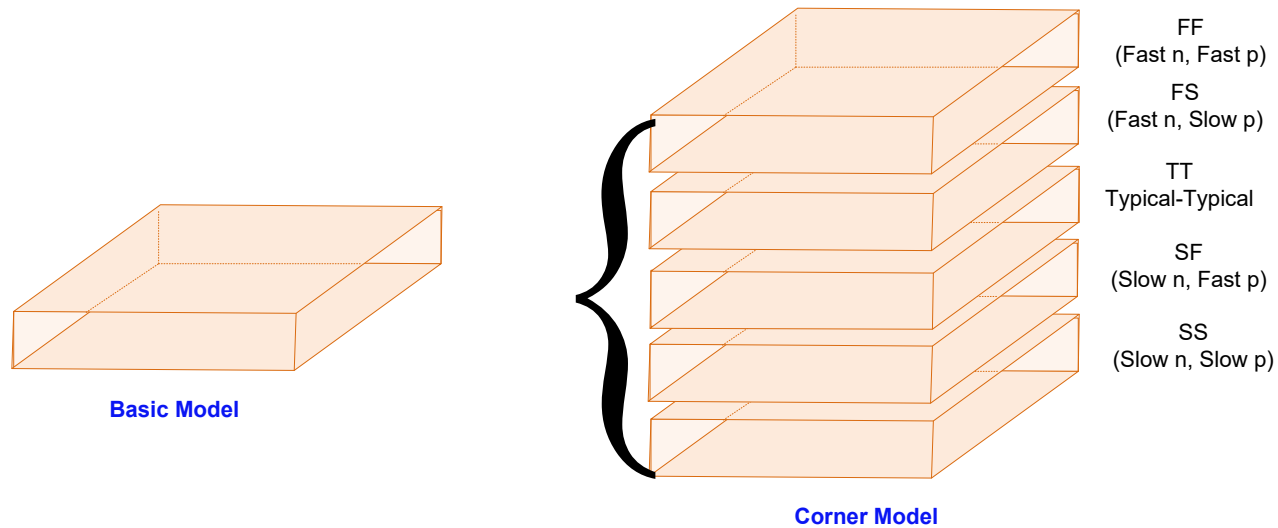
TT: typical-typical
 FF: fast n, fast p
 FS: fast n, slow p
 SF: slow n, fast p
 SS: slow n, slow p

With 4 corners, this model has 475 model parameters !

Hierarchical Model Comparisons



Corner Models



Applicable at any level in model hierarchy (same model, different parameters)

Often 4 corners (FF, FS, SF, SS) used but sometimes many more

Designers must provide enough robustness so good yield at all corners



Stay Safe and Stay Healthy !

End of Lecture 17